

Development of Vertex Detector for ILC

Proposal of SOI sensor for ILC: SOFIST
SOI sensor for **F**ine measurement of **S**pace and **T**ime

Miho Yamada (KEK)

yamadami@post.kek.jp

and SOI PIXEL R&D Group

SOI Satellite Meeting, Strasbourg, France

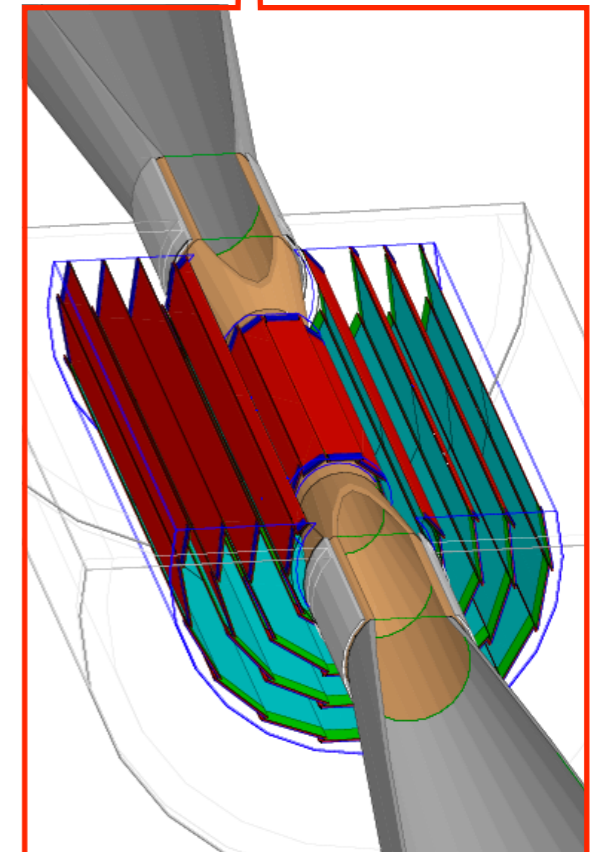
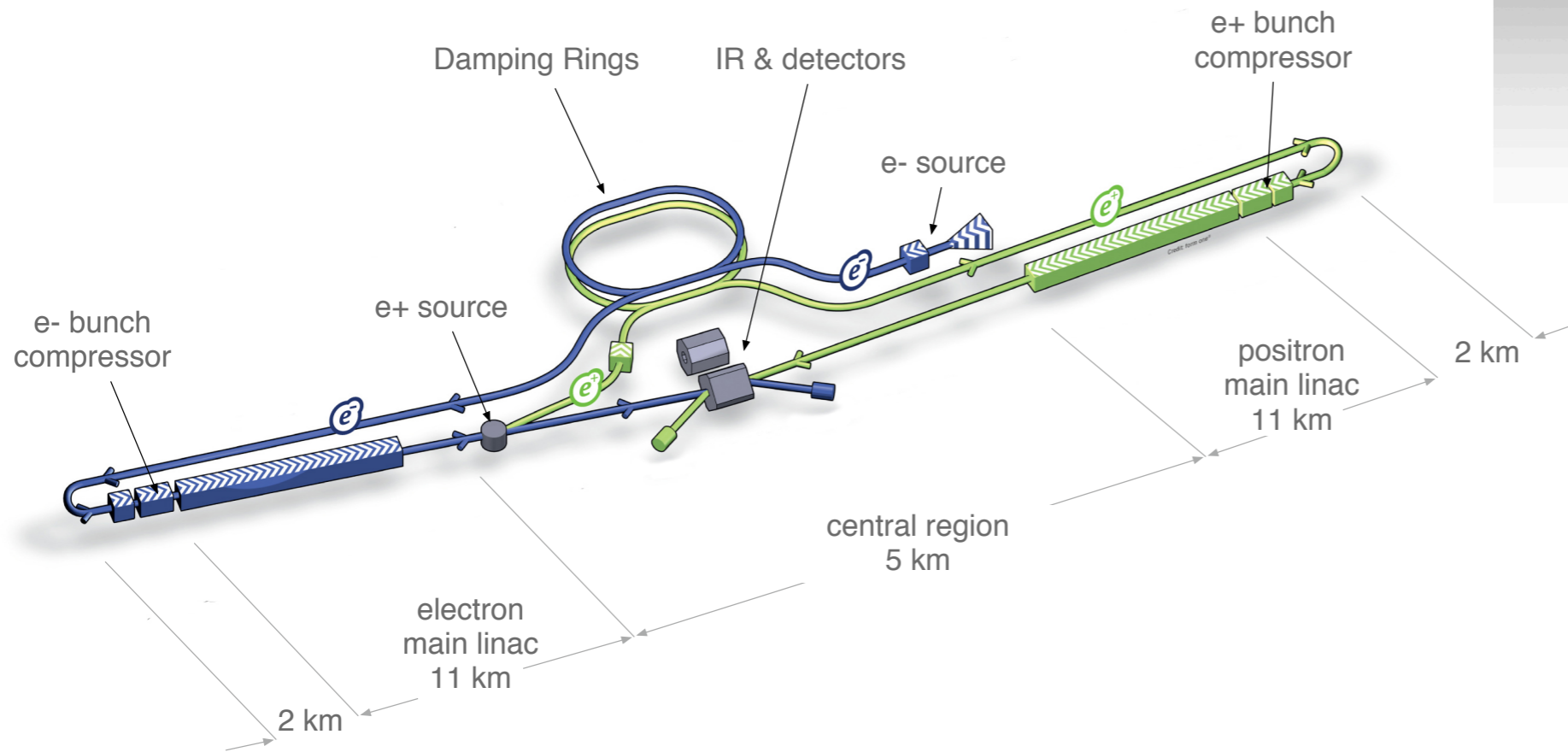
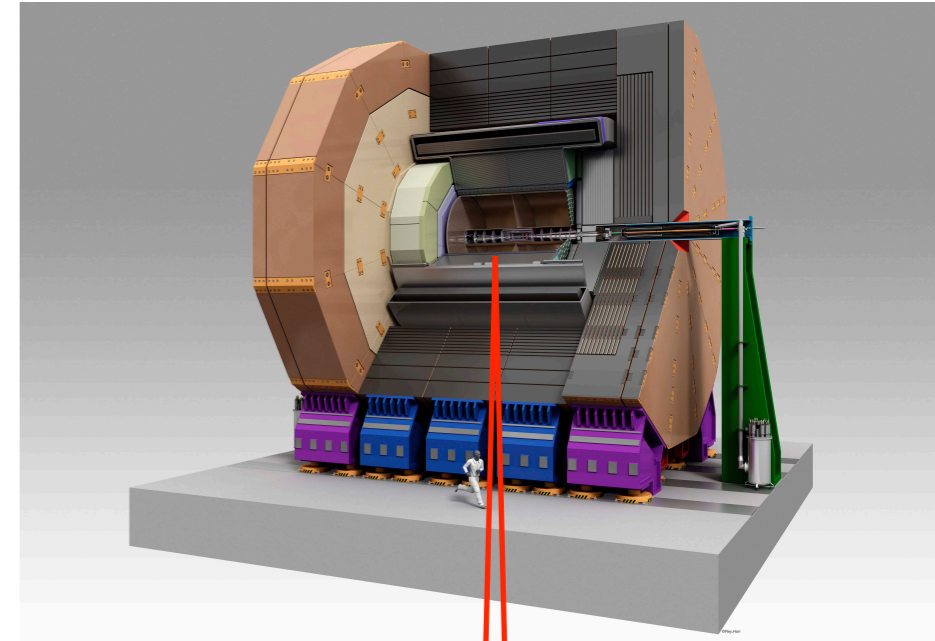
May. 9th, 2017

ILC Experiment

ILC Experiment

- e^+e^- linear collider
- Center of mass energy: 250 - 500 GeV (extendable to 1 TeV)
- Precise measurement of the Higgs boson
- Search for beyond the Standard Model

ILC detector concept (ILD)



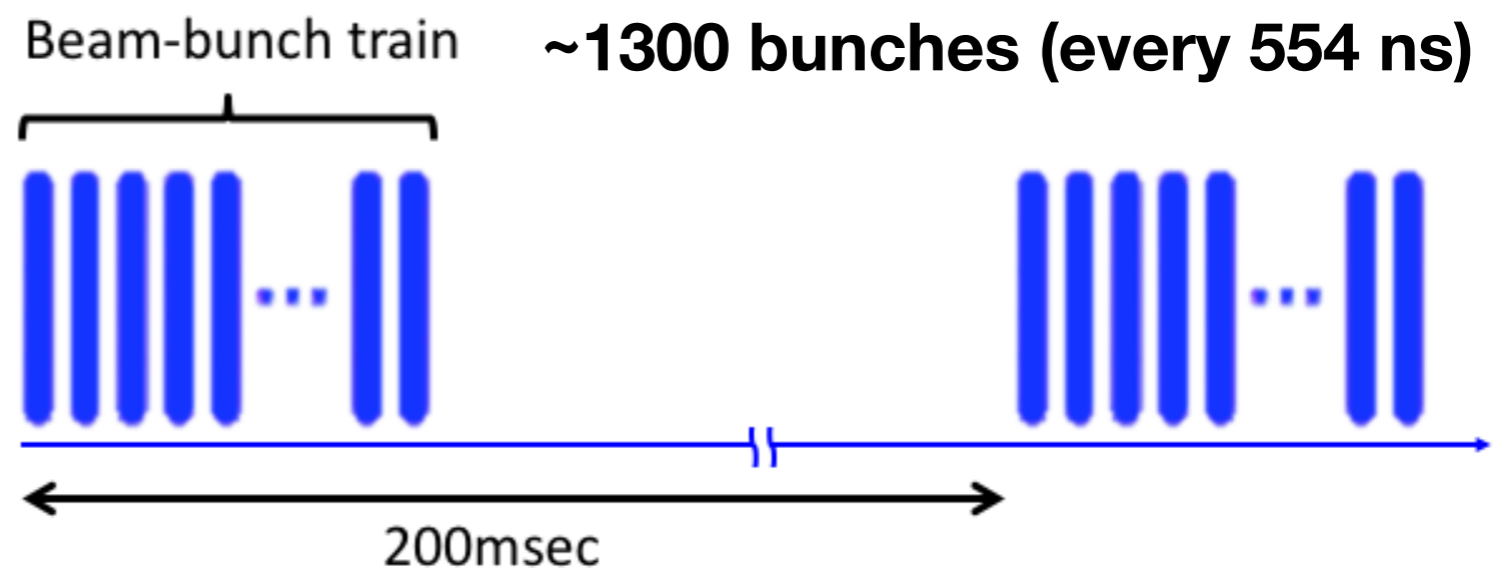
Vertex detector geometry (VTX-SL)

ILC Vertex detector

Requirements:

- 1) Single point resolution: better than $3 \mu\text{m}$
Pixel size: $\sim 20 \times 20 \mu\text{m}^2$
- 2) Time resolution: single-crossing (554 ns interval) time resolution
- 3) Detector occupancy: $< 2 \%$
- 4) Low material budget: $X \leq 0.1 - 0.2 \% X_0 / \text{Layer}$
corresponds to $\sim 100 - 200 \mu\text{m Si}$, including supports, cables and cooling
low-power ASICs ($\sim 50 \text{ mW/cm}^2$) + gas-flow cooling
- 5) Radiation hardness:
TID : $< 1 \text{ kGy / year}$
NIEL: $< 10^{11} \text{ 1MeV } n_{\text{eq}} / \text{cm}^2 / \text{year}$

We are designing and evaluating prototype pixel sensor with SOI technology to fulfill the requirements.



Functions for ILC Vertex Detector

Necessary functions for the ILC vertex detector:

- Single point resolution

Pixel size: less than $20\ \mu\text{m}$

Calculate weighted center of charges (Charges are spread among multi pixels).

→ Record an analog signal of a hit.

- Timing resolution

Bunch crossing occurs every 554 ns in 1-msec-long bunch train with an interval 200 ms.

Identify a collision bunch of a hit to reconstruct a event.

→ Record a time stamp of a hit.

- Detector occupancy

Hit information have to hold during 1 beam-bunch train.

Increase detector occupancy.

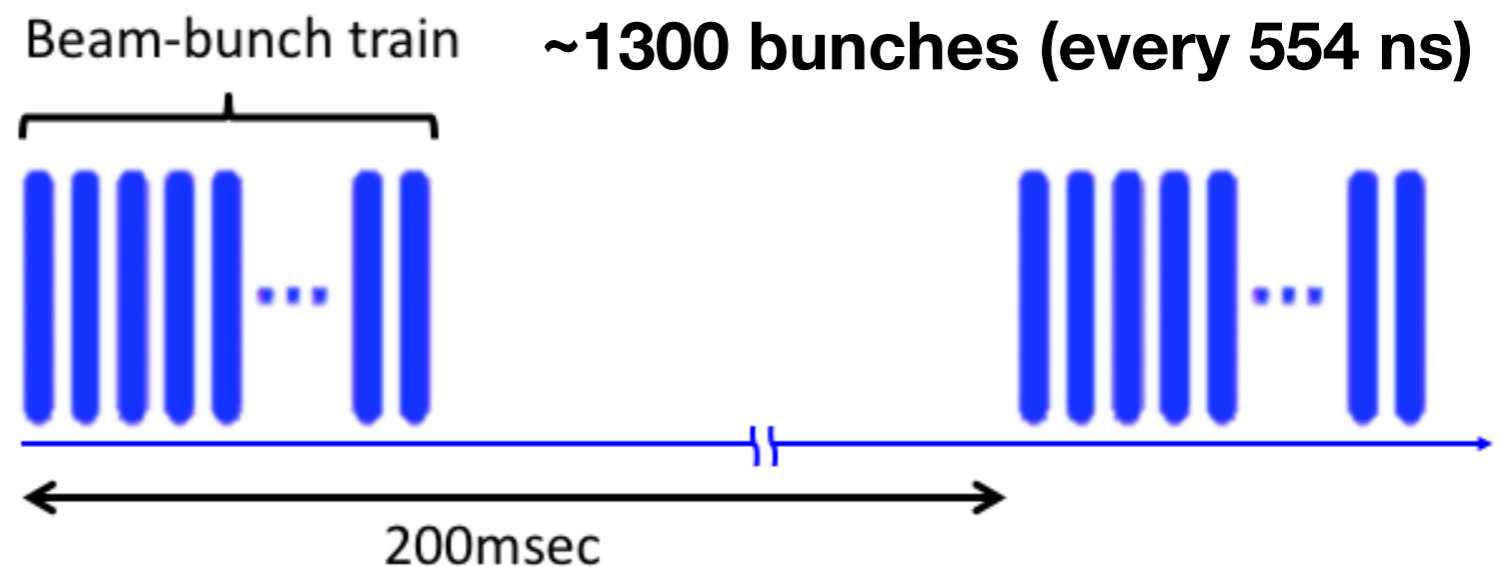
→ Need multiple memories

- High speed data transfer

Data have to be send to backend before next bunch train injection.

→ Reduce a data to transfer.

We designed a prototype pixel detector
SOFIST.



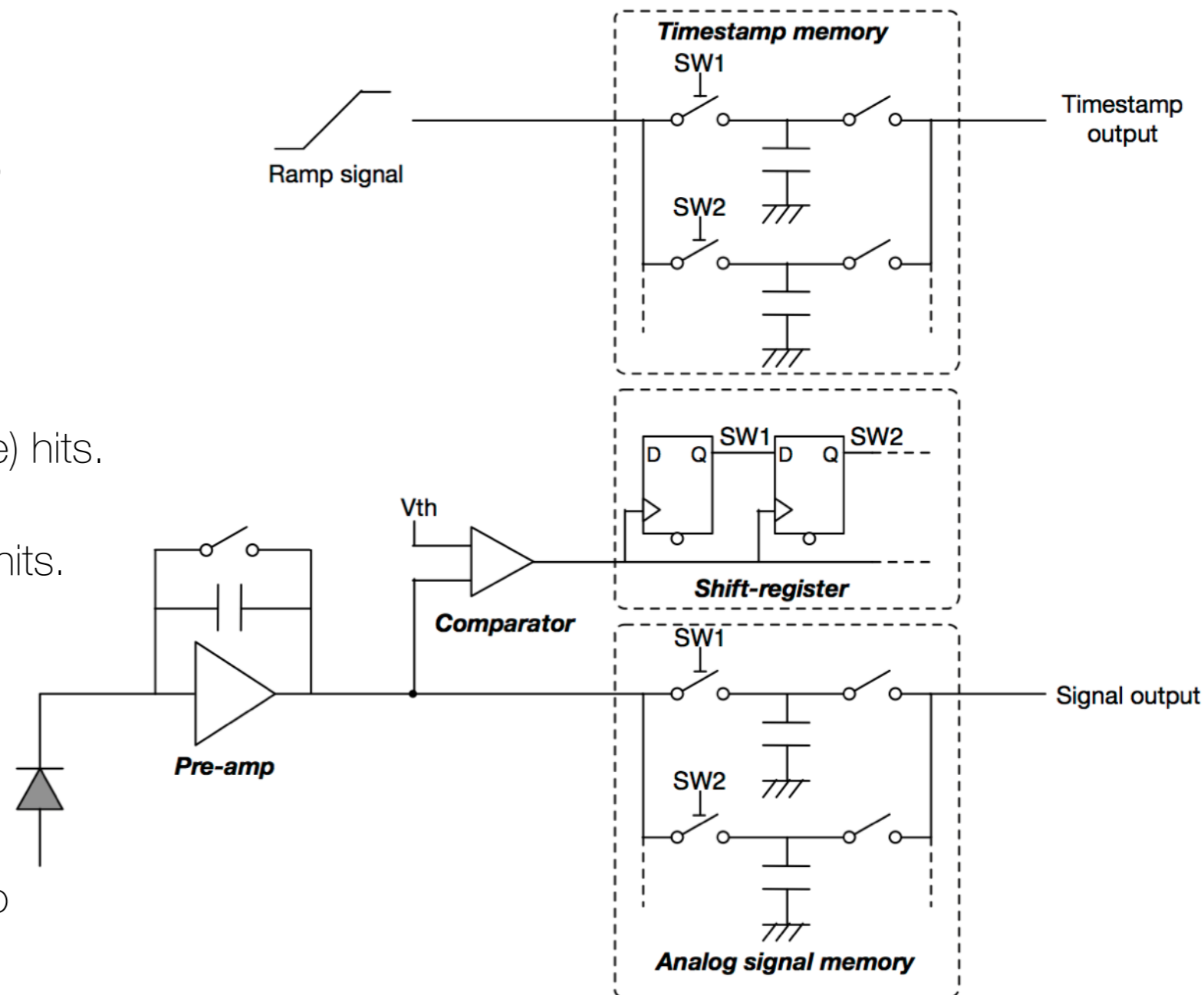
Architecture of SOFIST

In a Pixel

- Pre-amplifier
- Comparator
 - Keep the analog signal and time stamp if a signal exceeds a threshold V_{th} .
- Shift register
 - Latch for multiple memories.
- Analog signal memory
 - Store signal charges up to two (or more) hits.
- Time stamp circuit
 - Store time stamps up to two (or more) hits.

On Chip

- Column ADC
 - Digitize analog signal and time stamp.
- Zero-Suppression logic
 - Extract hit pixels and reduce the data to transfer to backend.

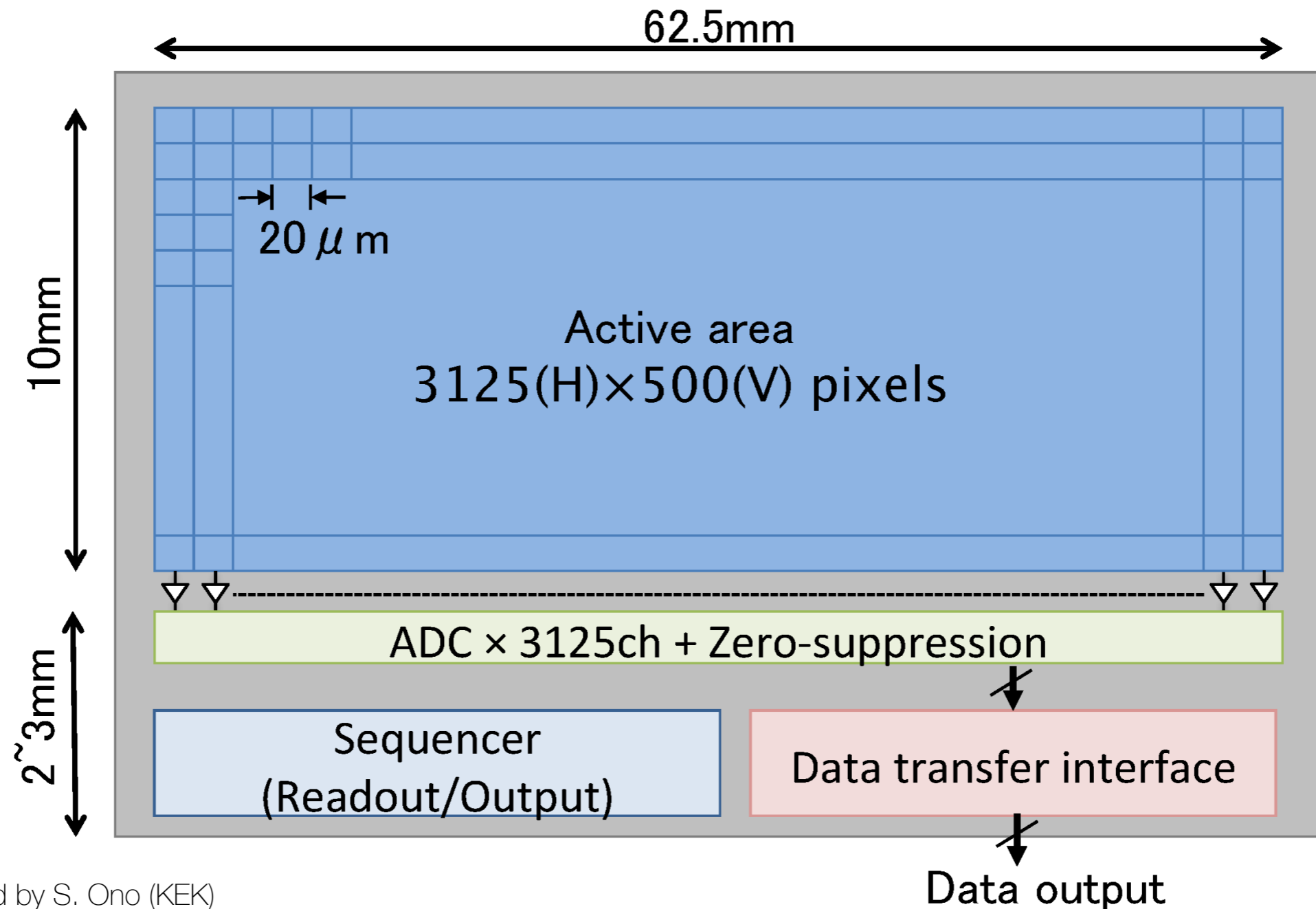


Designed by S. Ono (KEK)

SOI sensor for ILC: SOFIST

SOFIST: SOi sensor for Fine measurement of Space and Time

Conceptual SOI pixel sensor for the ILC (inner most layer of the vertex detector).



Designed by S. Ono (KEK)

SOFIST

MX1850

MX2040

MX2xxx

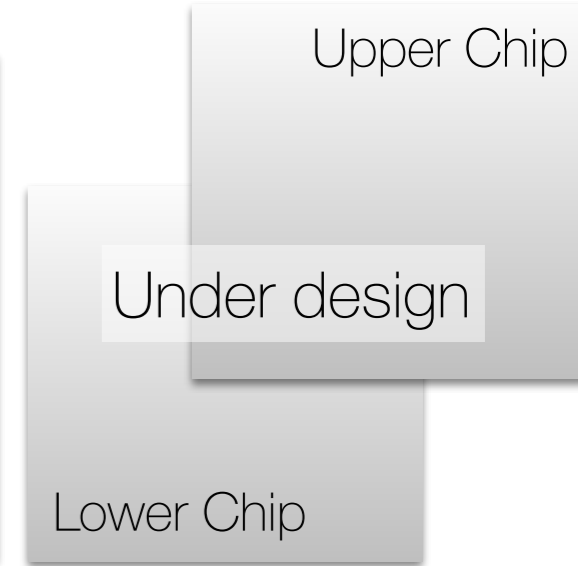
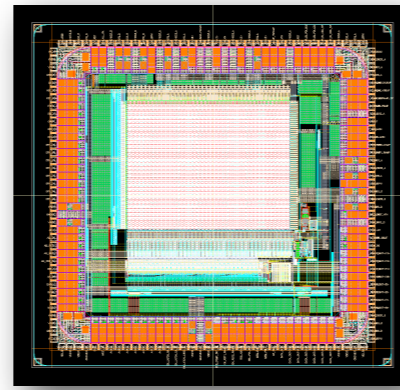
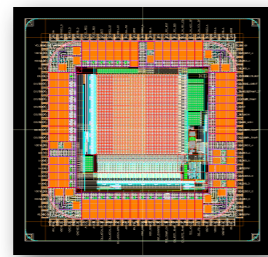
SOFIST

ver.1

ver.2

ver.3

ver.4 (3D)

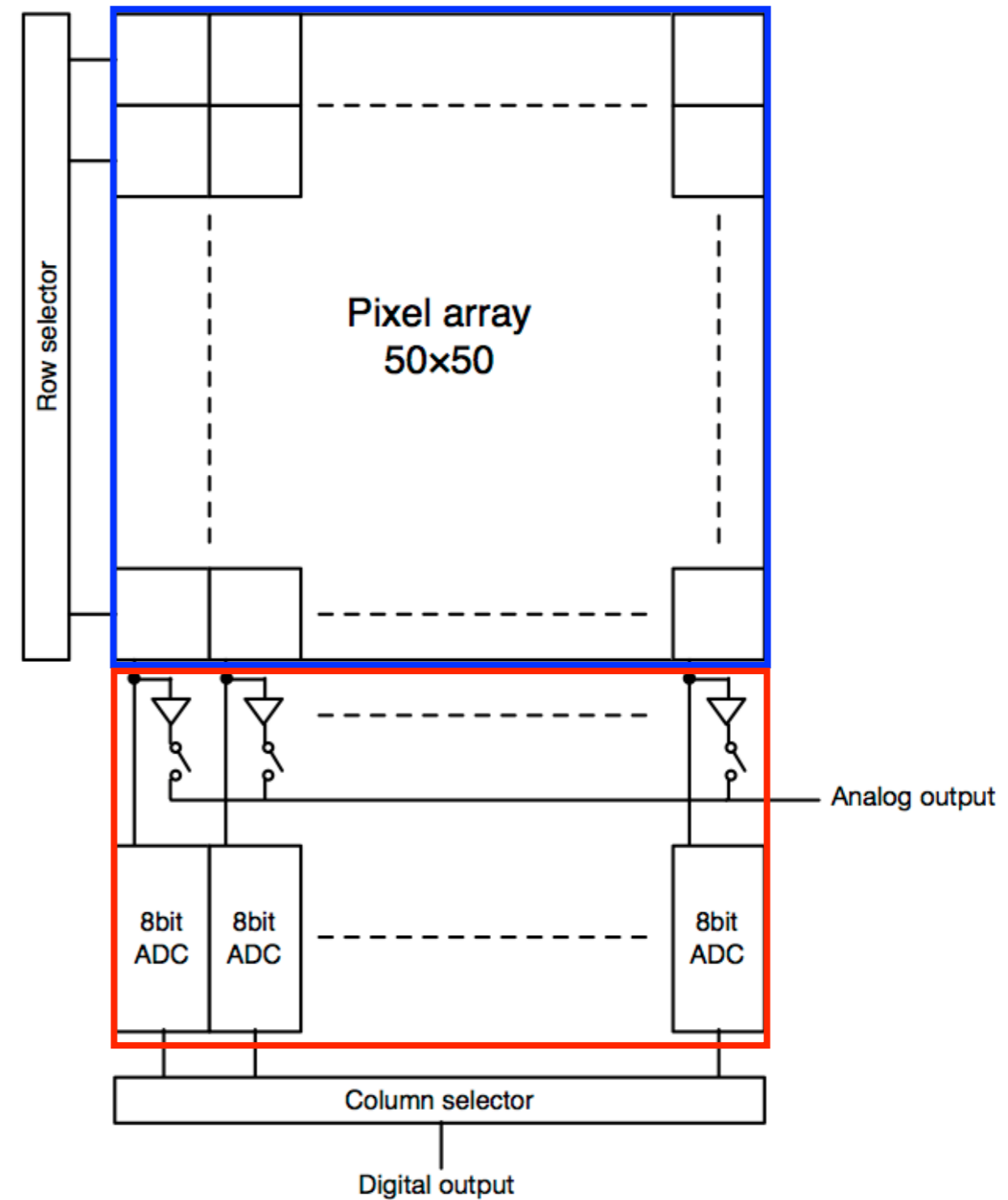
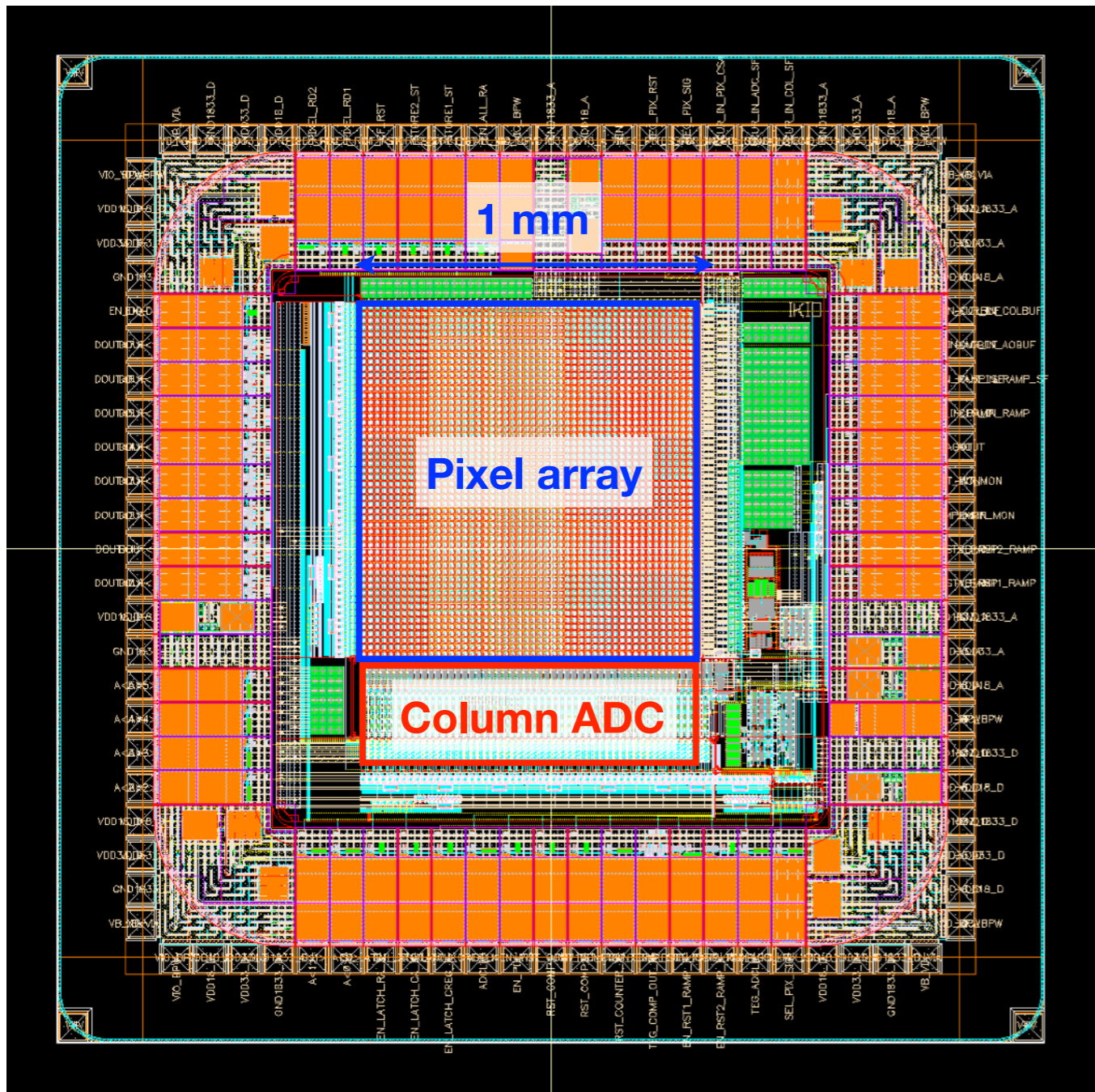


Chip Size (mm ²)	2.9 × 2.9	4.45 × 4.45	6 × 6	4.45 × 4.45
Pixel Size (μm ²)	20 × 20	25 × 25	30 × 30	20 × 20
Pixel Array	50 × 50	64 × 64 (Time Stamp) 1 × 64 (Analog Signal)	128 × 128	64 × 64
Functions (Pixel)	Pre. Amplifier (CSA) Analog signal memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 2) Analog signal memory (2 hits) or Time stamp memory (2 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)	Pre. Amplifier (CSA) Comparator (Chopper inverter) Shift register (DFF × 3) Analog signal memory (3 hits) Time stamp memory (3 hits)
Functions (On Chip)	Column ADC (8 bit)	Column ADC (8 bit) Zero-suppression logic	Column ADC (8 bit)	Column ADC (8 bit)
Wafer	FZ <i>n</i> -type (Single SOI)	Cz <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)	FZ <i>p</i> -type (Double SOI)
Wafer Resistivity (kΩ·cm)	2 ≤	1 ≤	3 - 10	3 - 10
Status	Delivered (Dec. 2015) Under evaluation	Delivered (Jan. 2017)	Under desing (Submit June 2017)	Under desing (Submit June 2017)

0.2 μm FD-SOI CMOS process by Lapis Semi. Co. Ltd.

SOFIST ver. 1

SOFIST ver.1



Pixel size: $20 \times 20 \mu\text{m}^2$
Chip size: $2.9 \times 2.9 \text{ mm}^2$
Active area: $1.0 \times 1.0 \text{ mm}^2$ (50 × 50 pixels)
Wafer: FZ *n*-type, Single SOI, 500 μm thickness

SOFIST ver.1

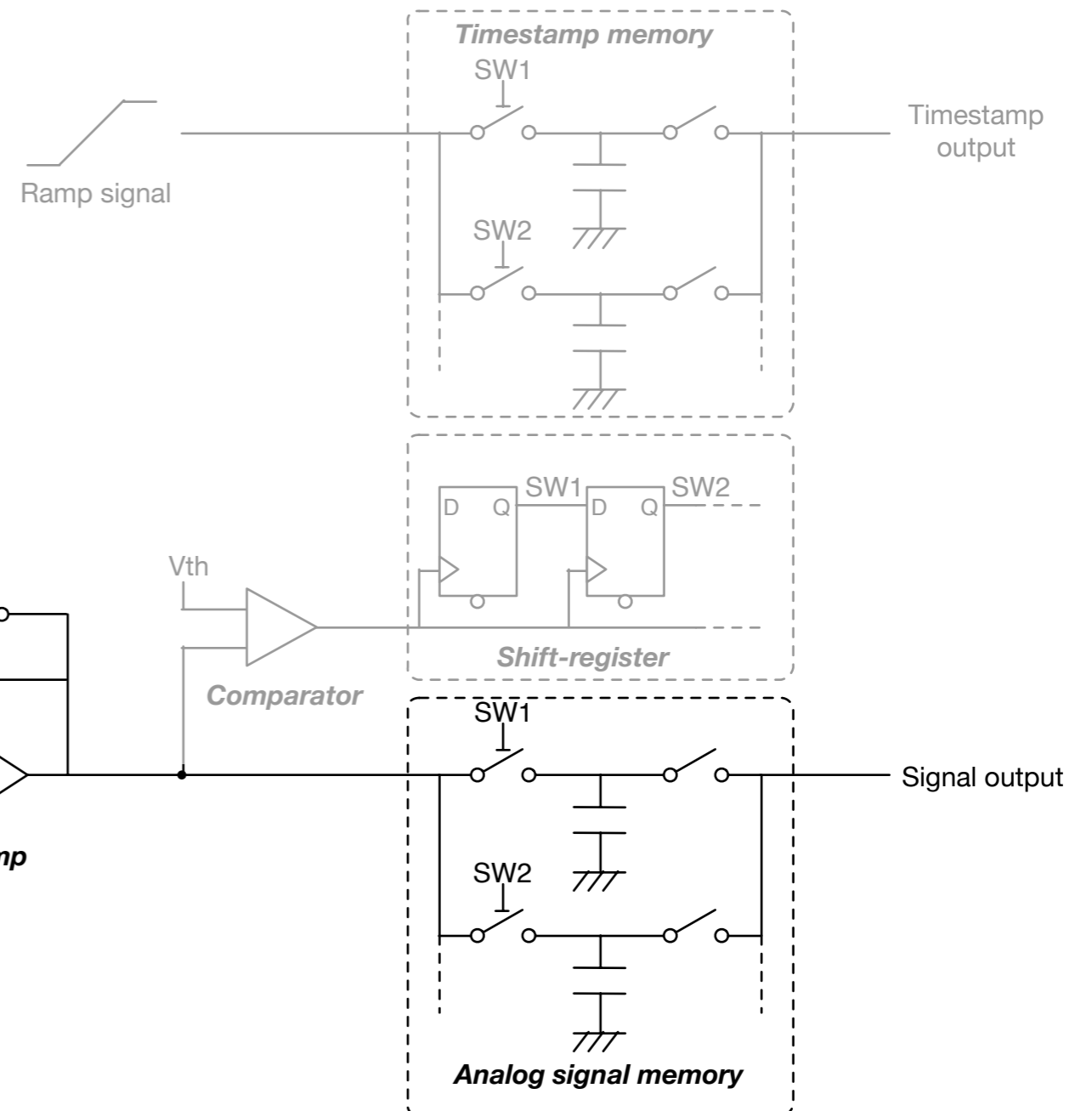
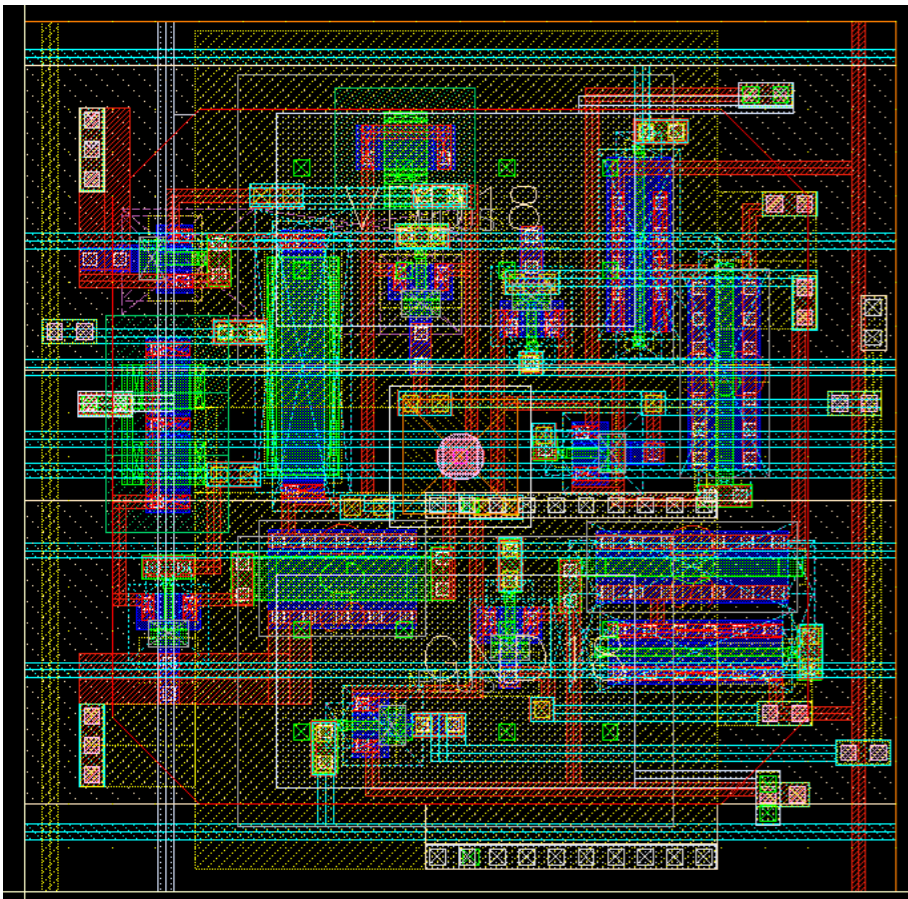
Pixel

- Pre. amplifier (Charge sensitive amplifier)
gain: 0.12 V/MIP (assuming 50 μm thick sensor)
- Analog signal memories (two memories)

On chip

8 bit column ADC

Pixel size: 20 \times 20 μm^2



Beam Test

SOFIST ver.1 Beam Test with FPIX2

at Fermilab Test Beam Facility (Jan. 20th - Feb. 8th, 2017)



Beam

120 GeV proton beam
1 spill: ~4 sec



Colleagues

SOFIST (KEK):

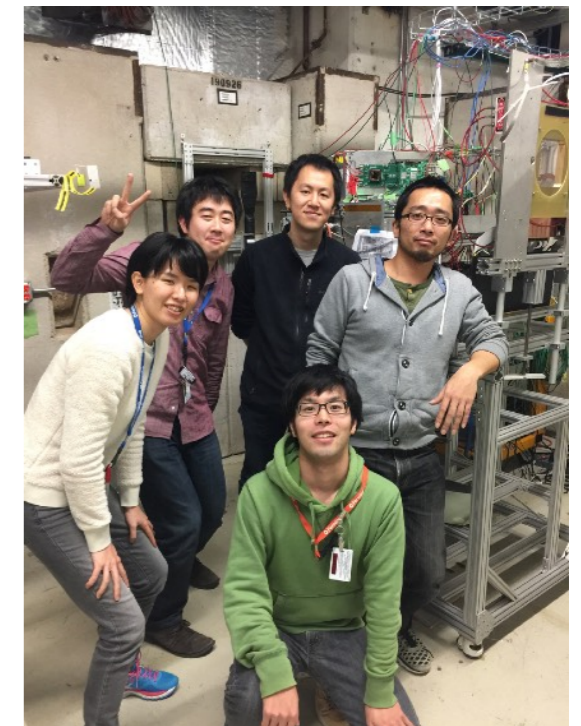
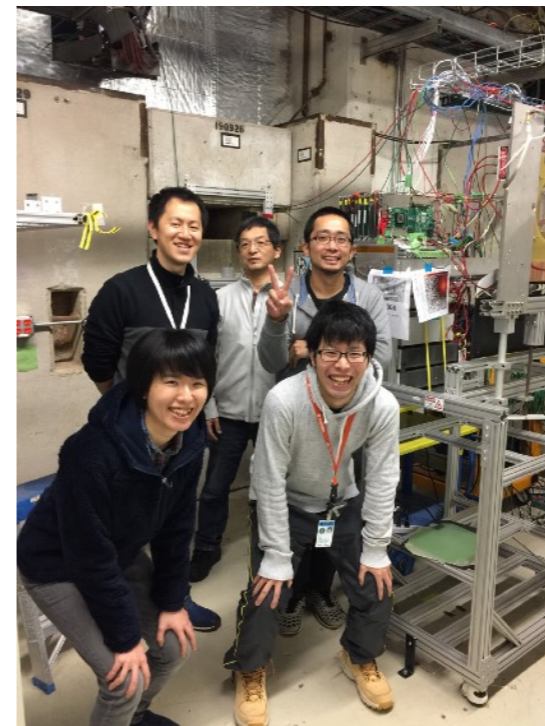
T. Tsuboyama, M. Togawa, S. Ono and M. Yamada

FPIX (Univ. Tsukuba):

D. Sekigawa and S. Endo

Evaluation

- S/N ratio
- Position resolution



Setup

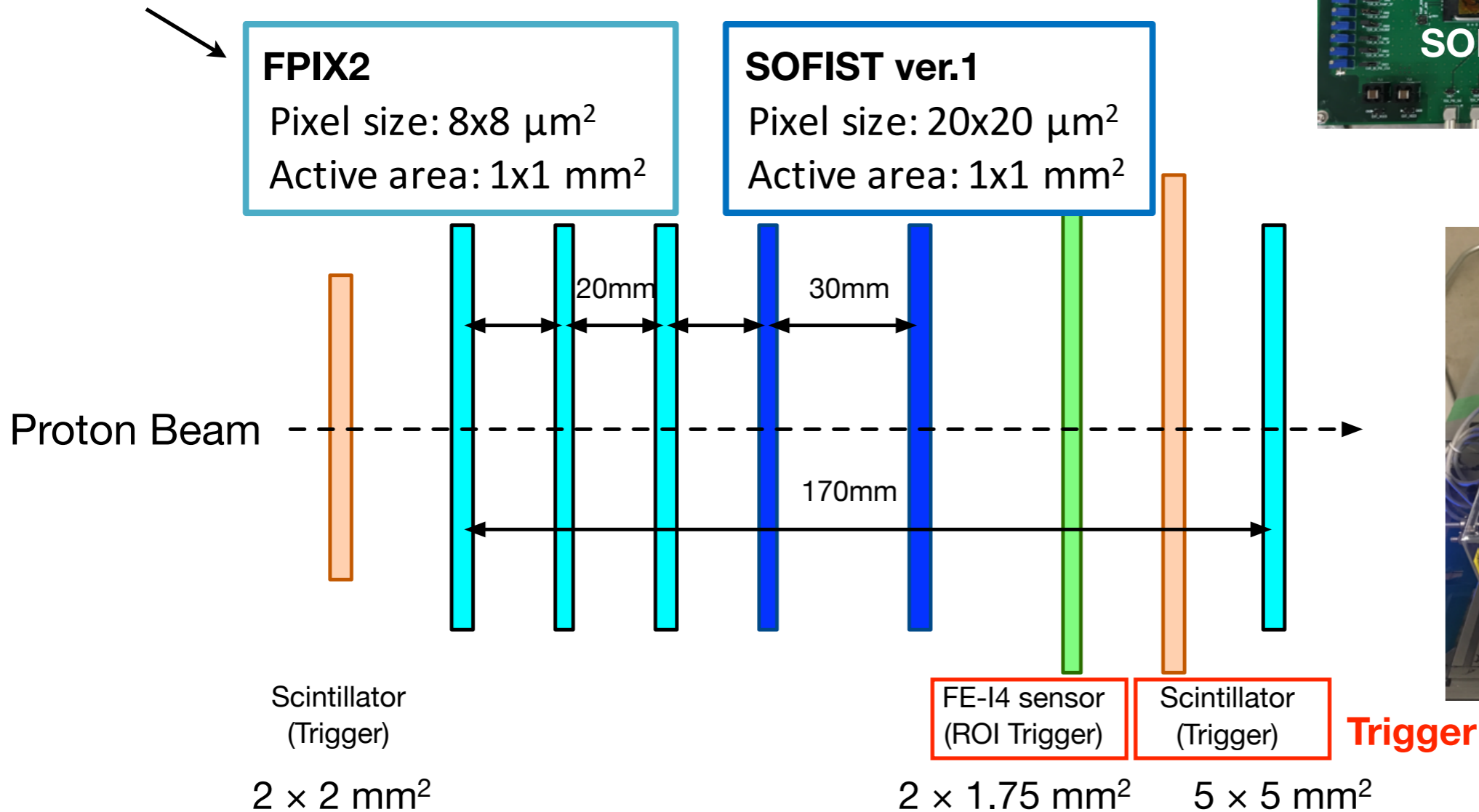
Trigger: ATLAS upgrade pixel sensor (FE-I4) & Scintillator (Downstream)

(Some data were taken by coincidence of two scintillators for checking the DAQ system.)

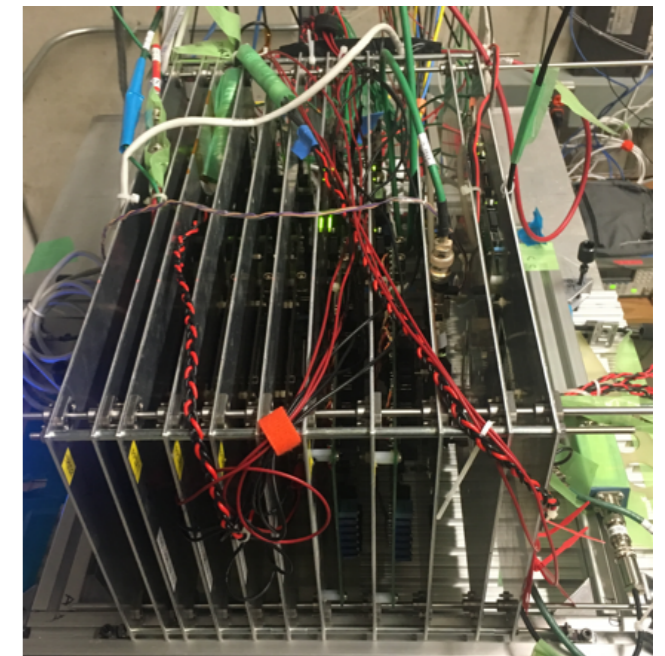
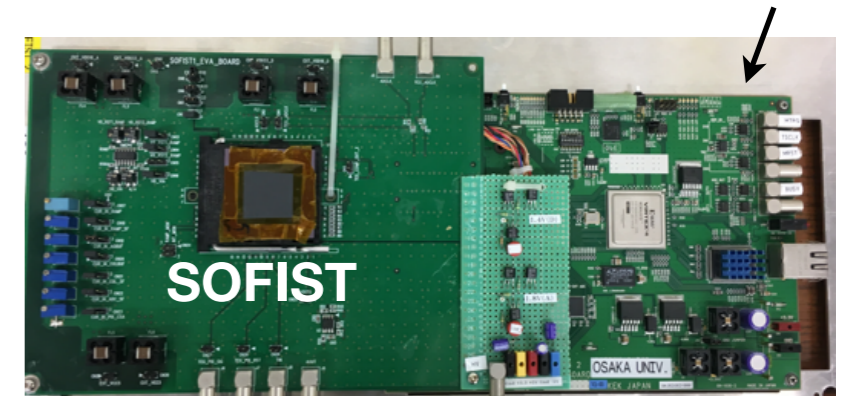
DAQ rate: ~300 events/s

Telescope for SOFIST

Reconstruct track with four layers of FPIX2.



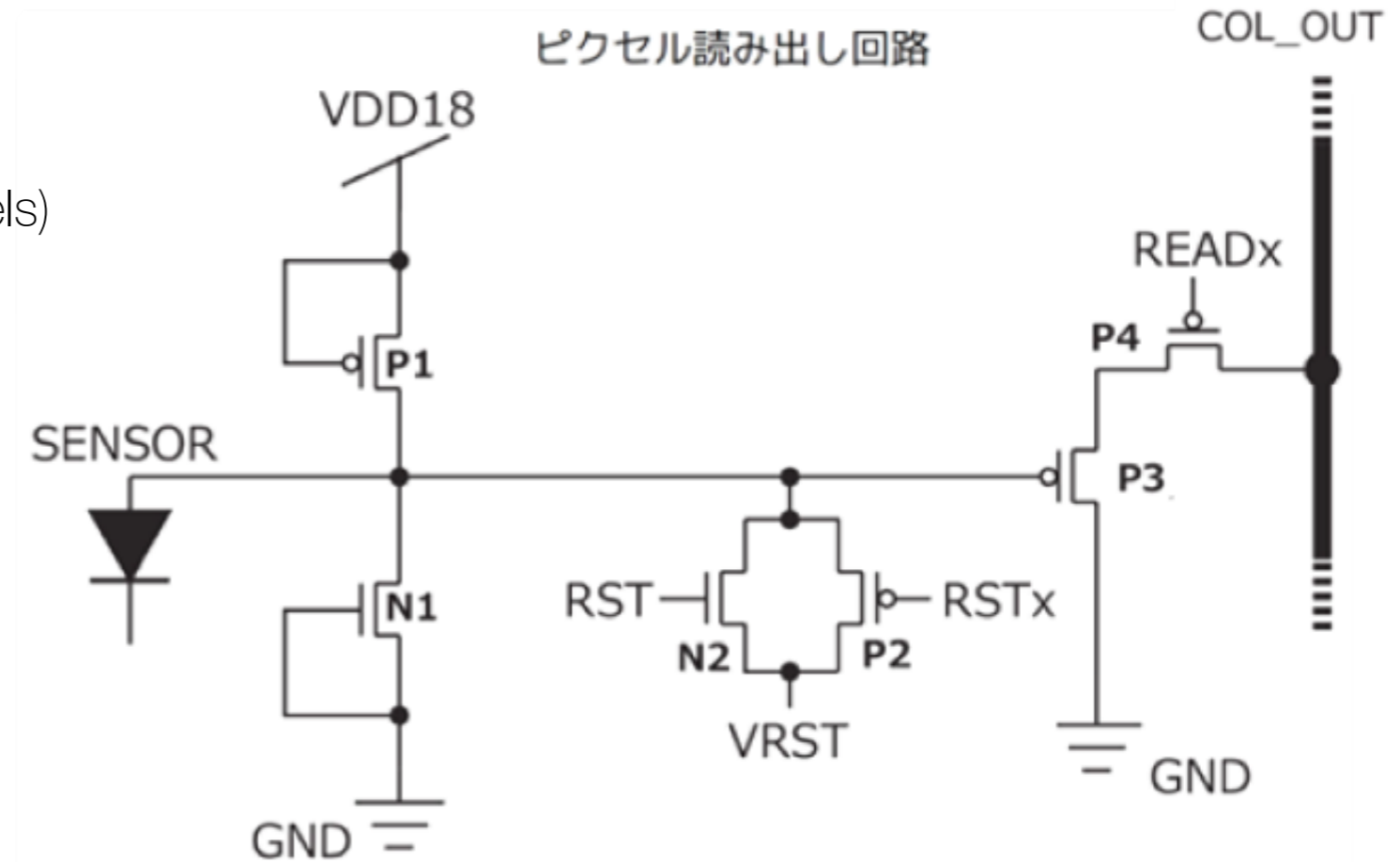
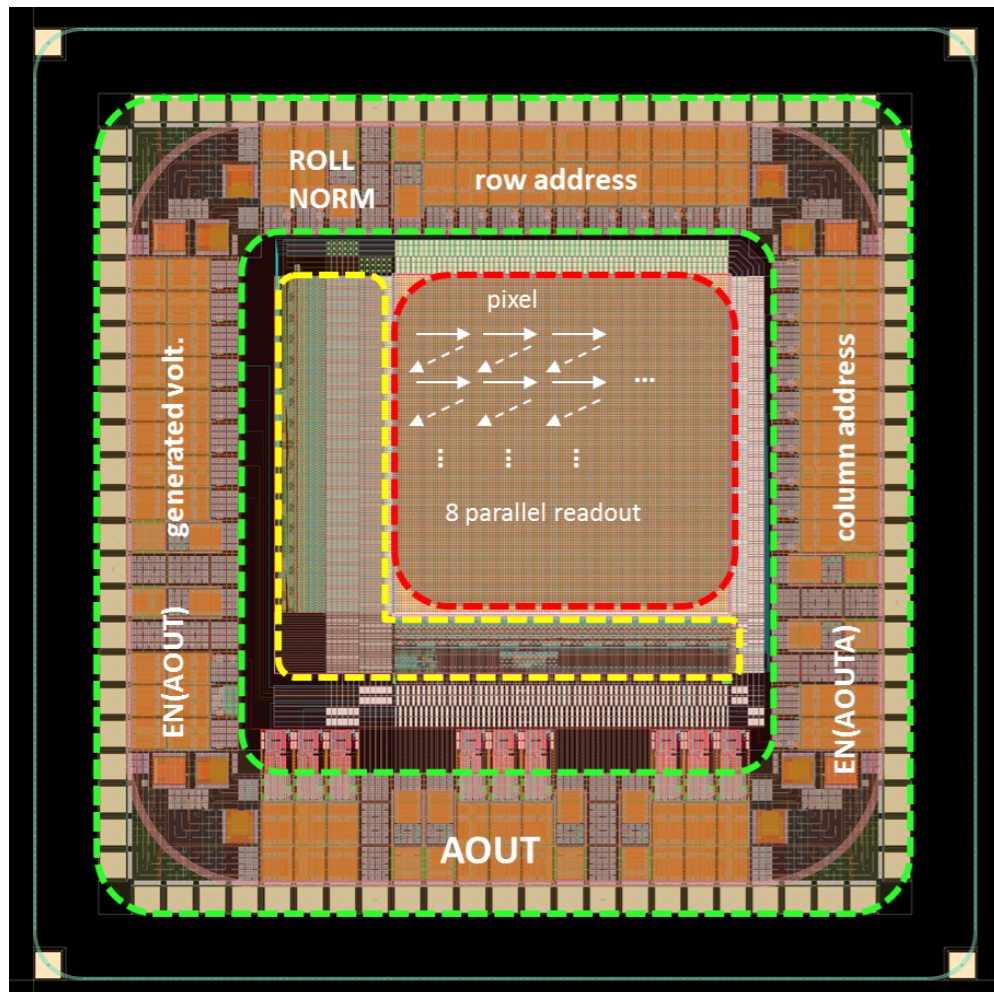
DAQ board (SEABAS2)



FPIX2

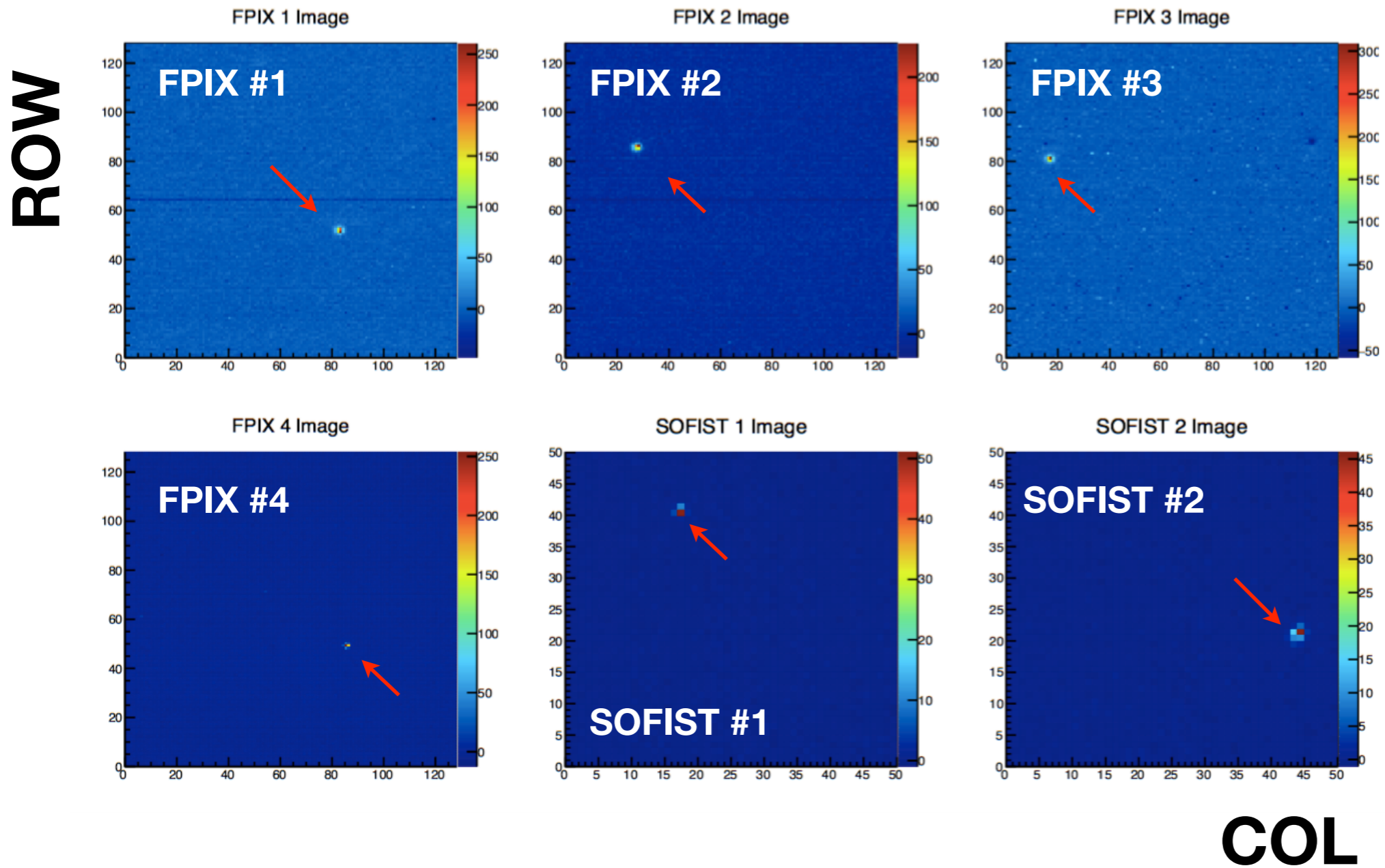
FPIX2 (SOI Pixel sensor)

- Chip size: $2.9 \times 2.9 \text{ mm}^2$
- Single-SOI (FZ *p*-type, $500 \mu\text{m}$)
- Pixel size: $8 \times 8 \mu\text{m}^2$
- Active area: $1024 \times 1024 \mu\text{m}^2$ (128×128 pixels)
- Readout: Rolling shutter, 8 line parallel
- 1 ms frame time
- External 12 bit ADC (SEABAS2)



Event Display

They are already subtracted their pedestal.



FPIX2

HV = 70 V (not fully depleted $\sim 400 \mu\text{m}$)
Reset cycle = 1 ms

SOFIST ver.1

HV = 130 V (fully depleted $\sim 500 \mu\text{m}$)
Reset cycle = $10 \mu\text{s}$

Cluster

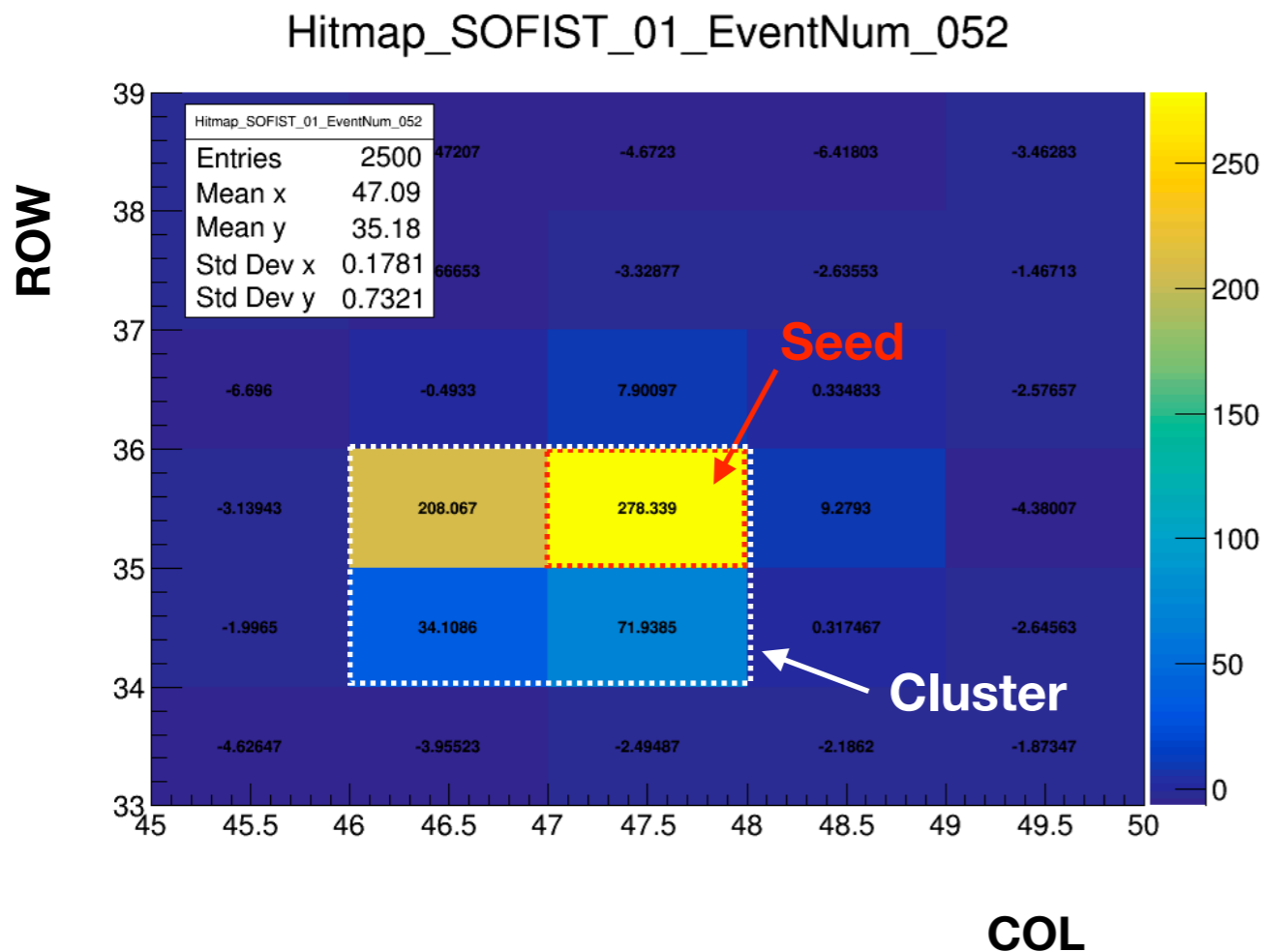
SOFIST setup

Readout: 12 bit external ADC (SEABAS2 onboard)

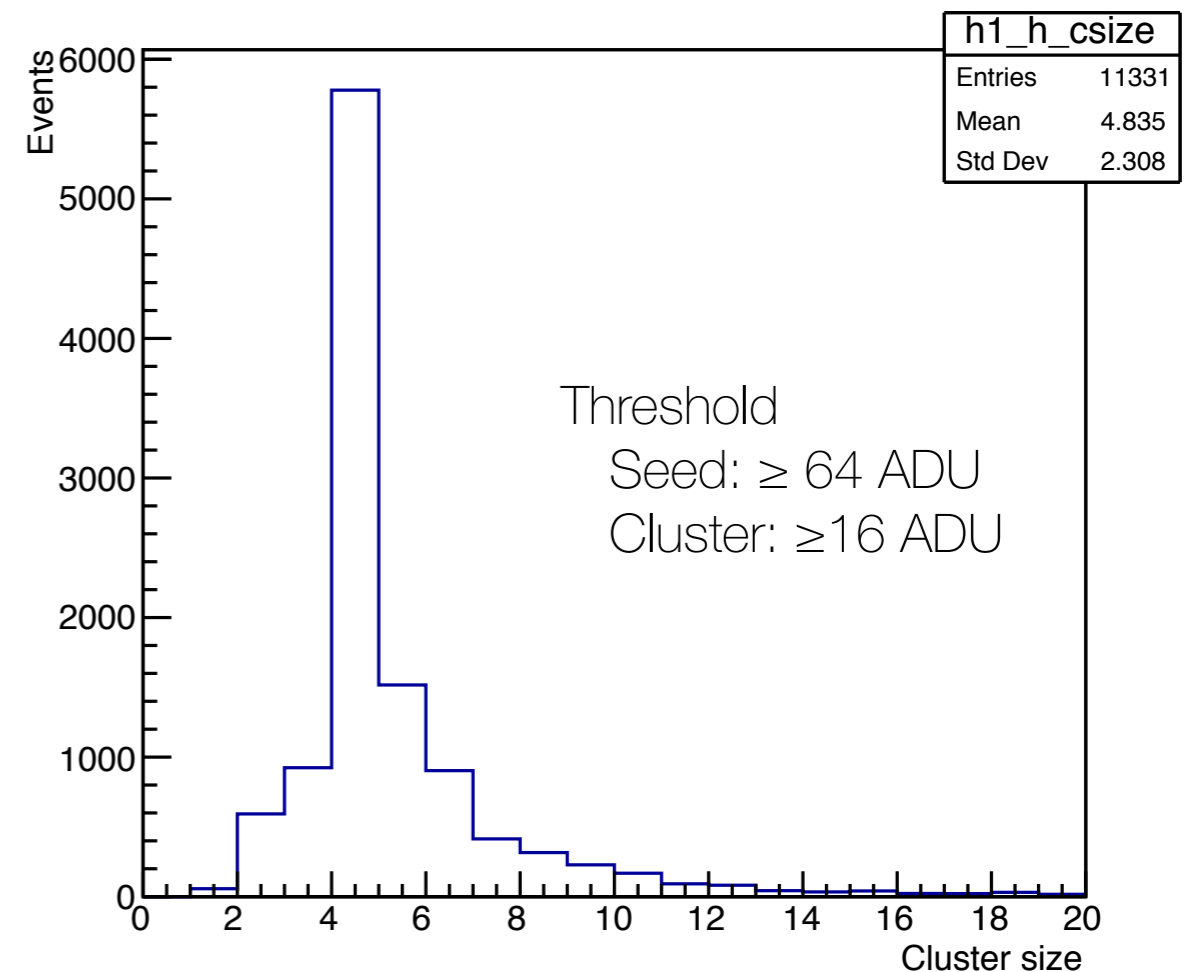
Bias voltage = 130 V

Clustering

- 1) find seed pixel which is ≥ 64 ADU.
- 2) add pixels which are ≥ 16 ADU to cluster.
- 3) check 2) for 6×6 pixels centered on the seed pixel.



Cluster Size



S/N

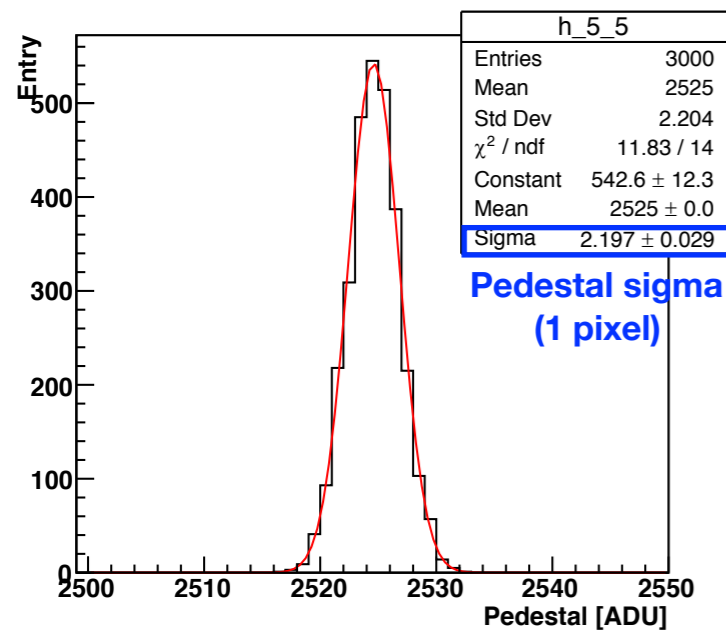
SOFIST setup

Readout: 12 bit external ADC (SEABAS2 onboard)
Bias voltage = 130 V

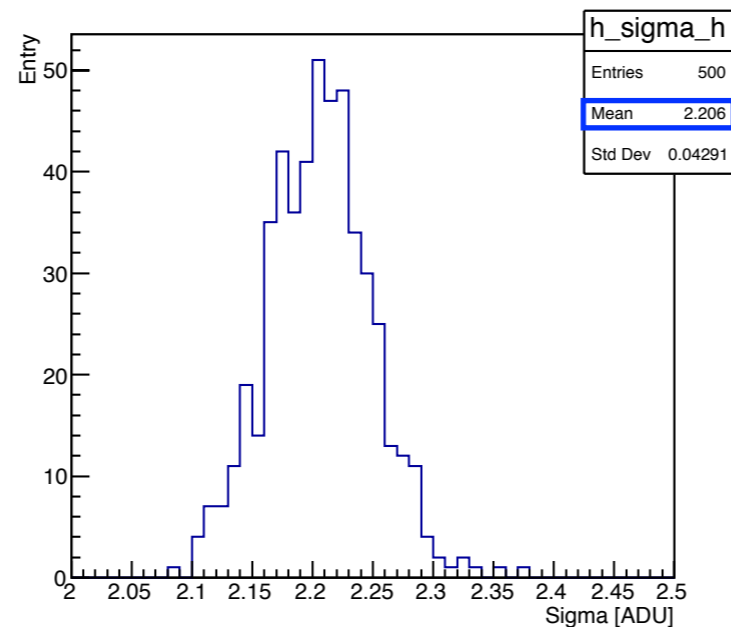
Clustering

- 1) find seed pixel which is ≥ 64 ADU.
- 2) add pixels which are ≥ 16 ADU to cluster.
- 3) check 2) for 6×6 pixels centered on the seed pixel.

Pedestal (1 pixel)

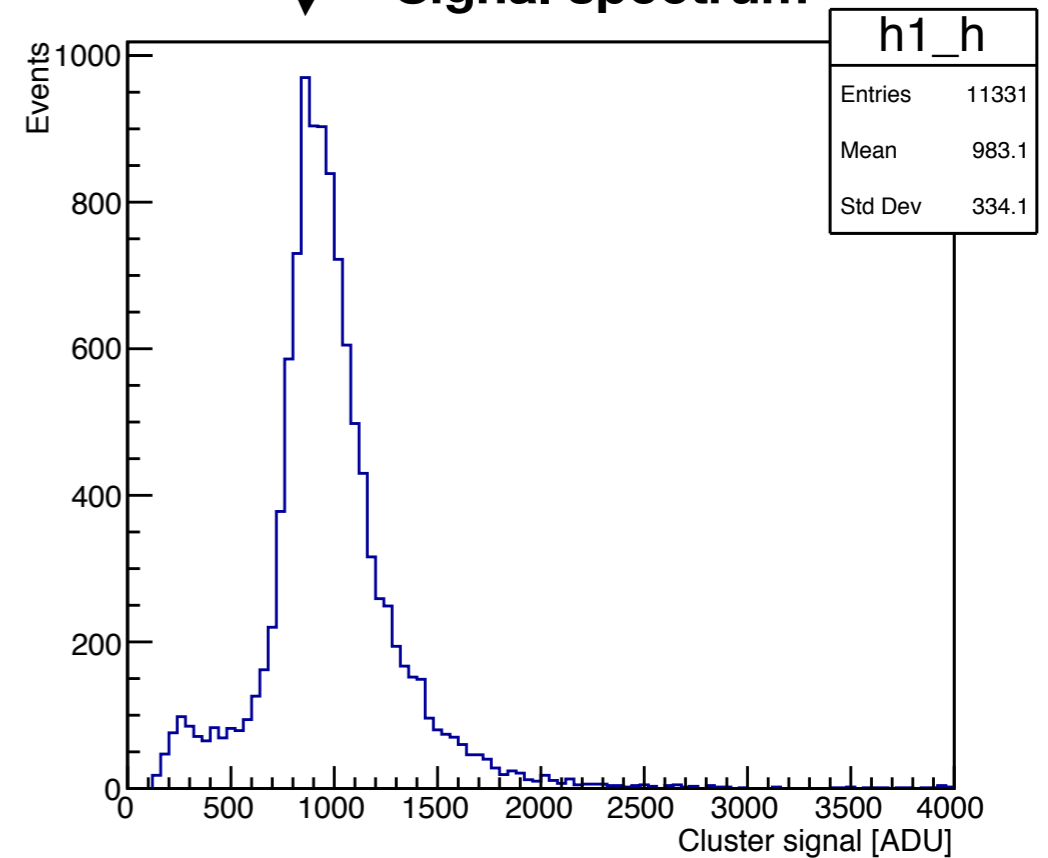


Pedestal sigma (Noise) Mean = 2.2 (All pixels)



Signal peak: ~800 ADU

Signal spectrum



Signal to Noise ratio

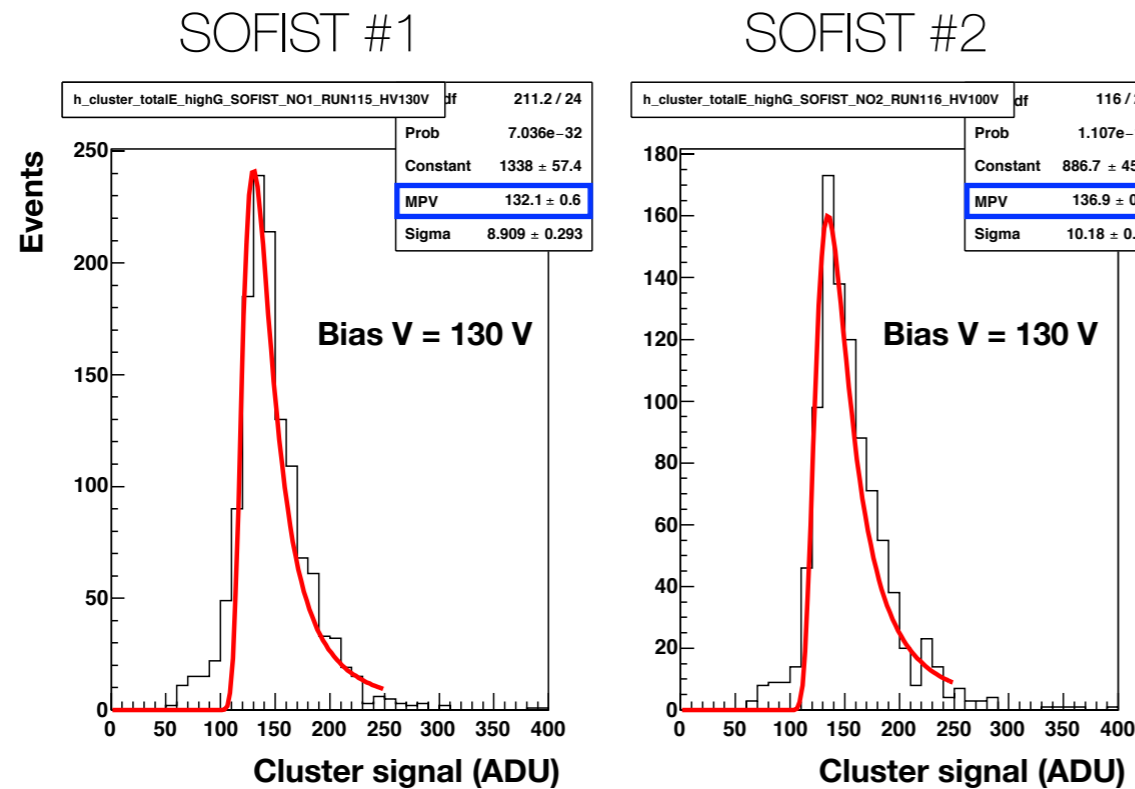
Signal peak = ~800 ADU
Pixel noise = ~2.2 ADU



S/N ~ 360 (Full depletion of 500 μm thickness)

HV Scan

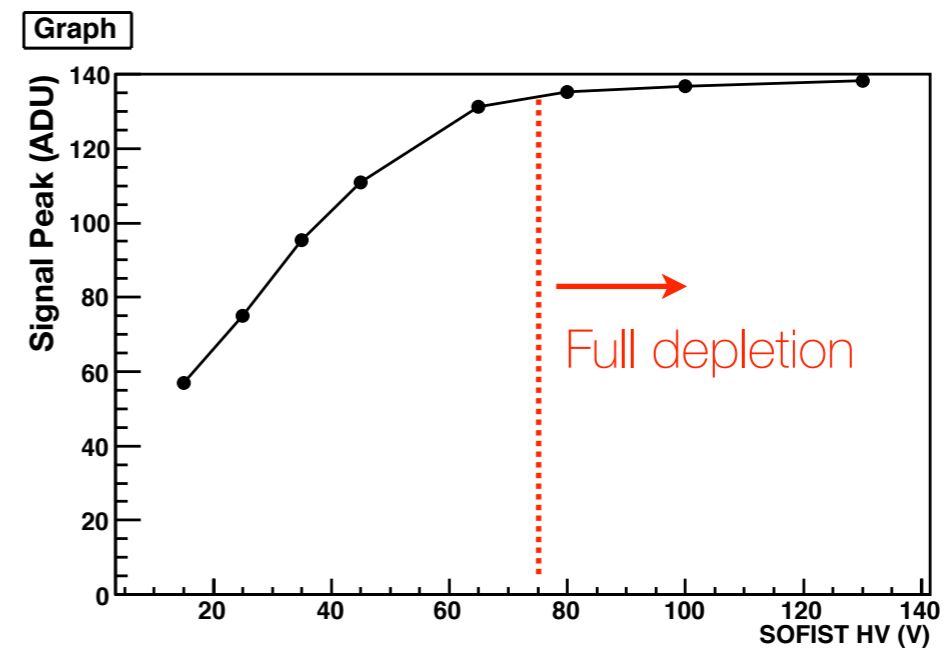
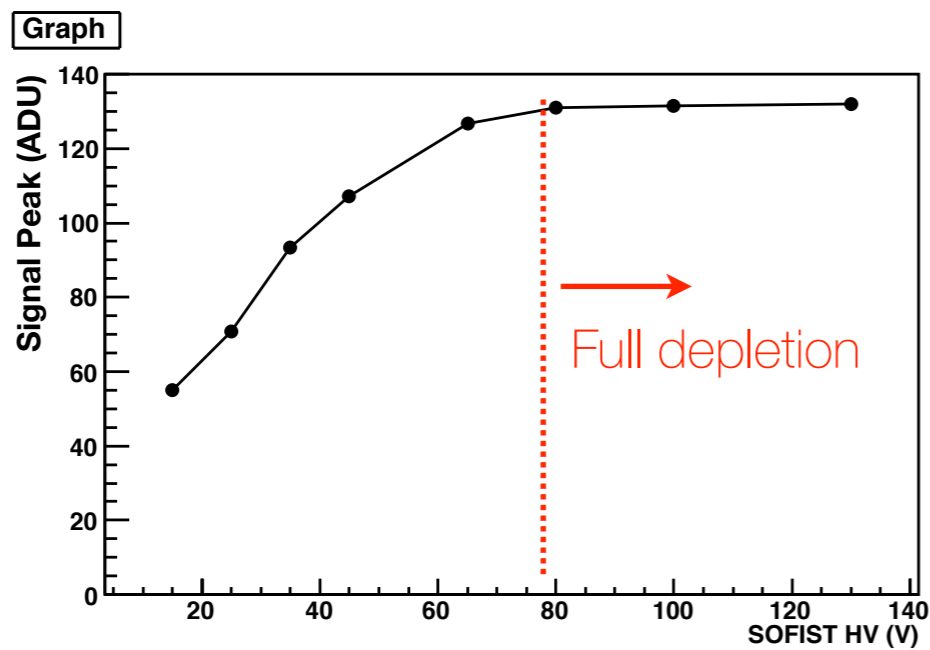
Signal peak dependence on a bias voltage.



Signal spectrum fitted by Landau function.
(Readout: On chip 8 bit ADC)

→ Plot MPV as a function of the bias voltage.

Full depletion voltage is ~80 V for 500 μm.



Tracking and Residual

Sensor alignment (software)

Parallel shift (x and y) and rotation (around the z-axis).

Hit position reconstruction

Calculate weighted center of charges (6 × 6 pixels).

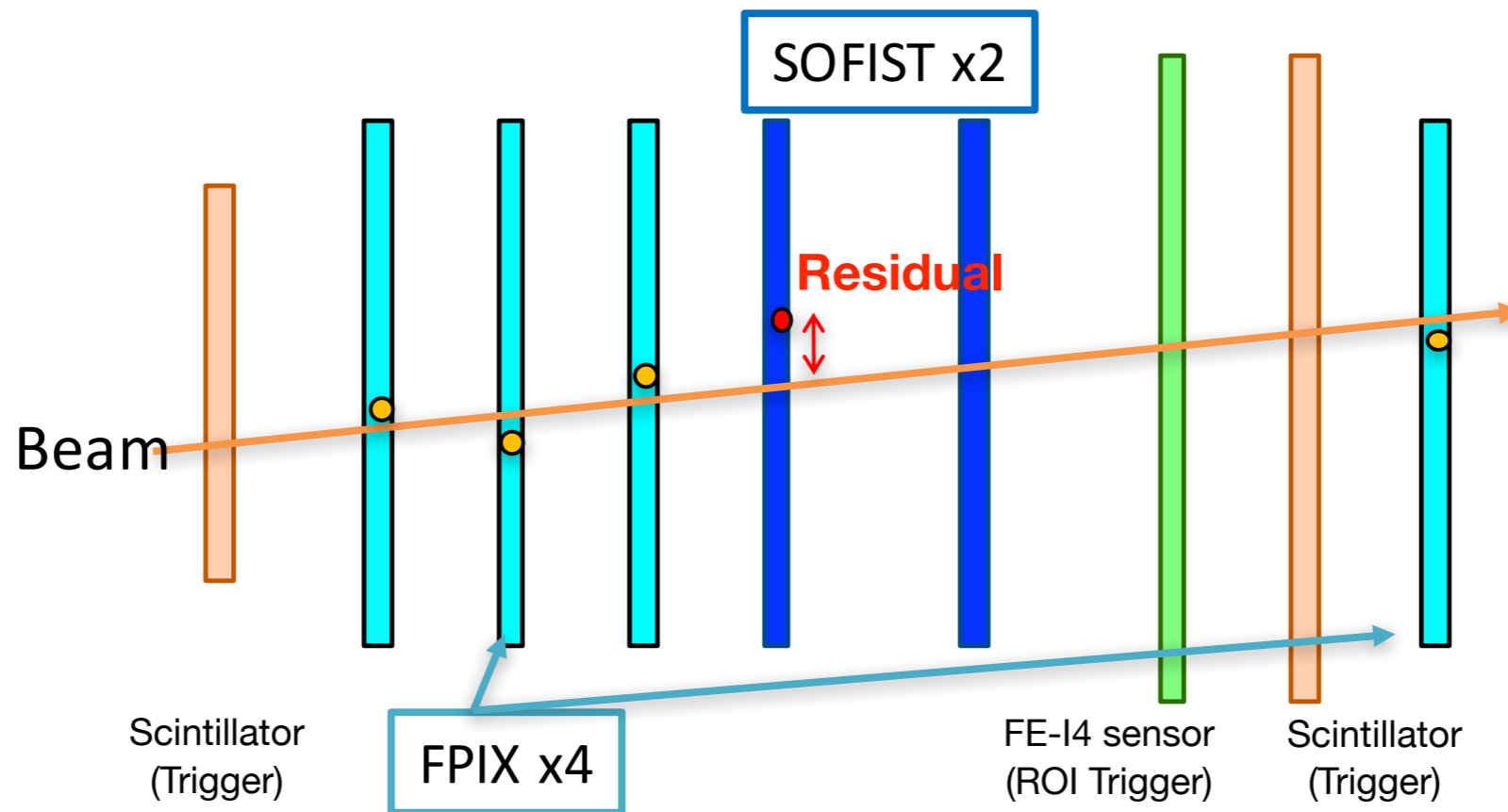
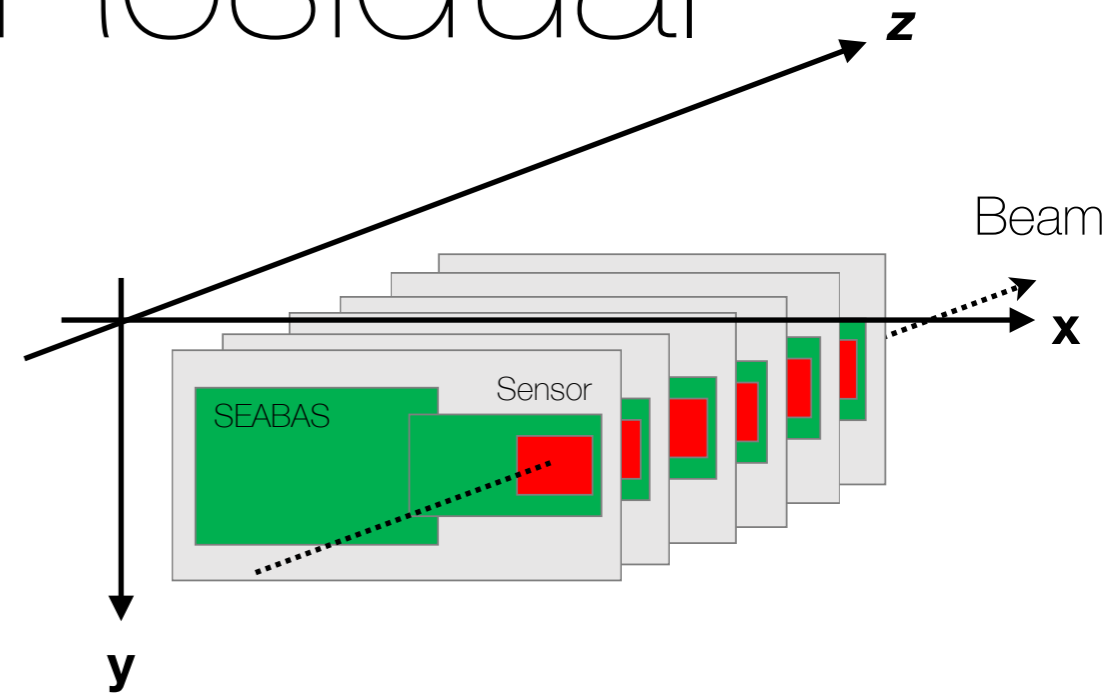
Track reconstruction

Find track candidates by four layers of FPIX.

The track that has the minimum chi2 is chosen for calculating the residual.

Residual

Difference between reconstructed track and actual hit on the SOFIST.

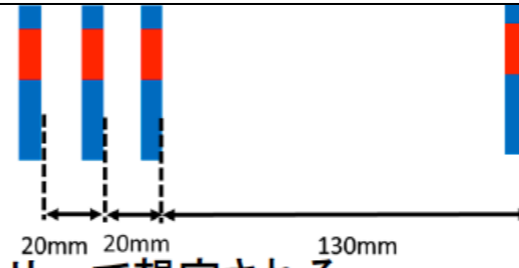


FPIX Residual

Tracking for FPIX

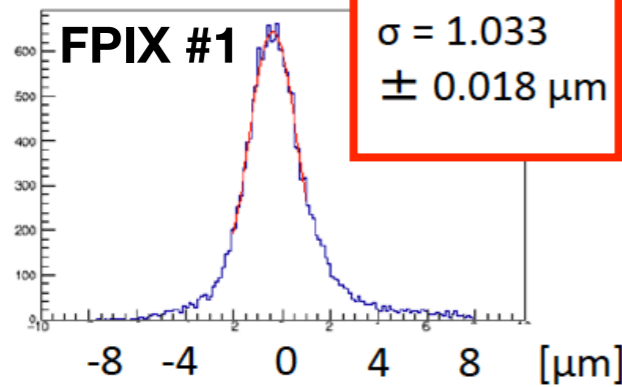
Reconstruct track with three layers of FPIX without DUT.

残差分布

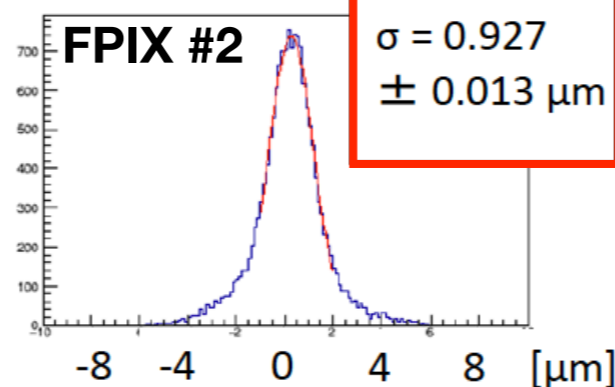


評価センサー以外の3枚から再構成したトラックの評価センサーで想定されるヒット位置と実際のヒット位置の差のピークをガウス関数でフィット

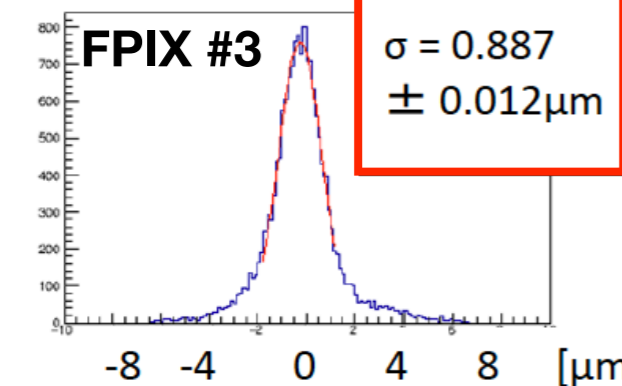
1枚目



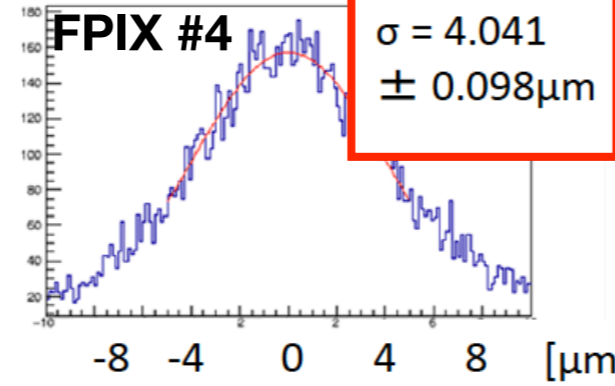
2枚目



3枚目



4枚目



2枚目、3枚目においてサブミクロンスケールの分布の拡がりを確認

D. Sekikawa (Univ. Tsukuba)
JPS 72nd annual meeting, Mar. 2017

FPIX #2 and 3 achieved residual better than 1 μm .

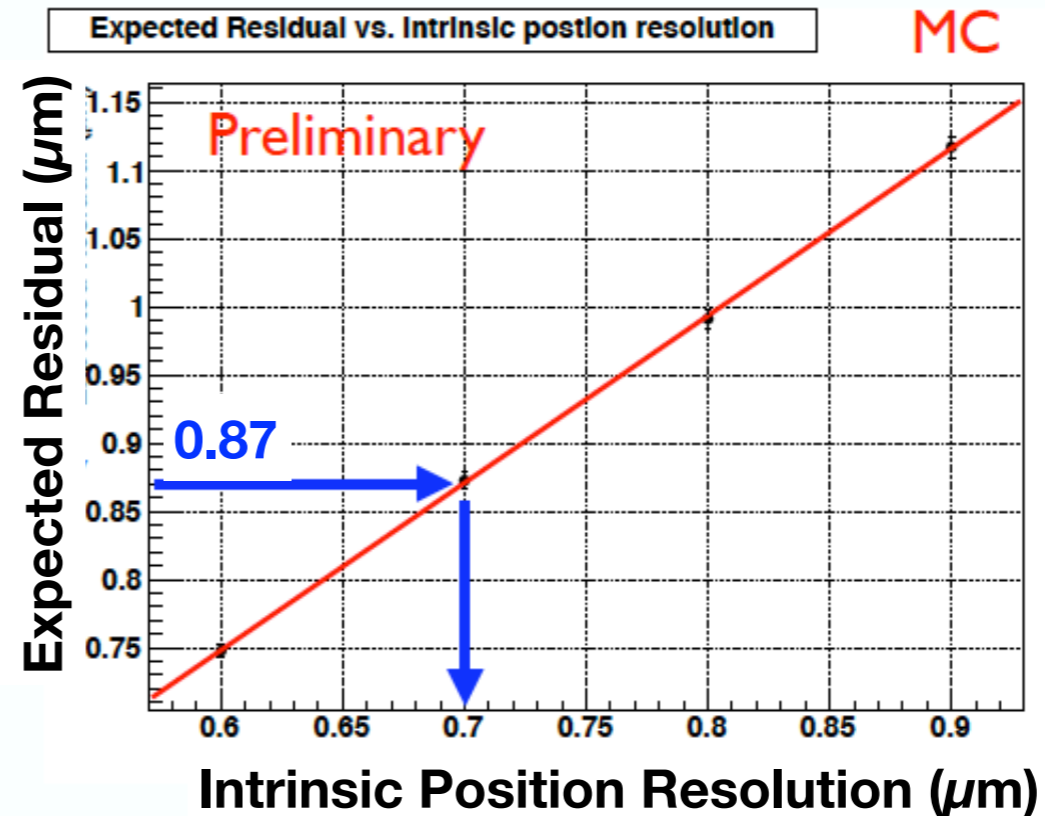
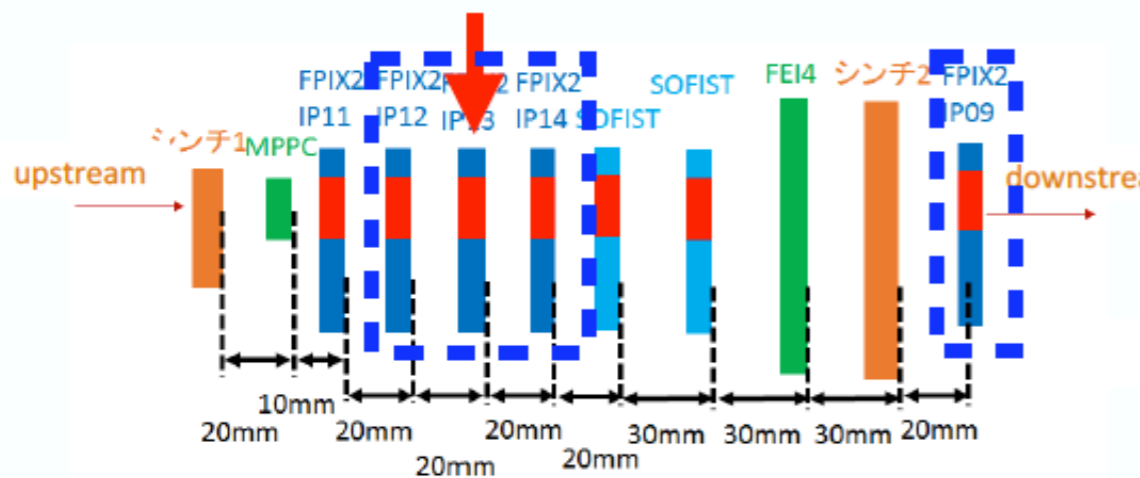
FPIX Position Resolution

FPIX

M. Togawa (KEK)
 LC Vertex Detector Workshop, Ringberg
 May 2nd, 2017

The position resolution of FPIX2 demonstrated by MC

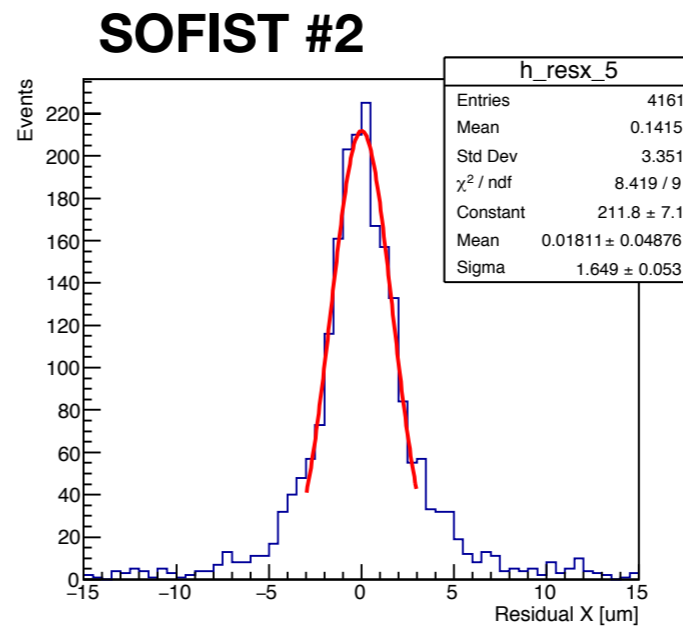
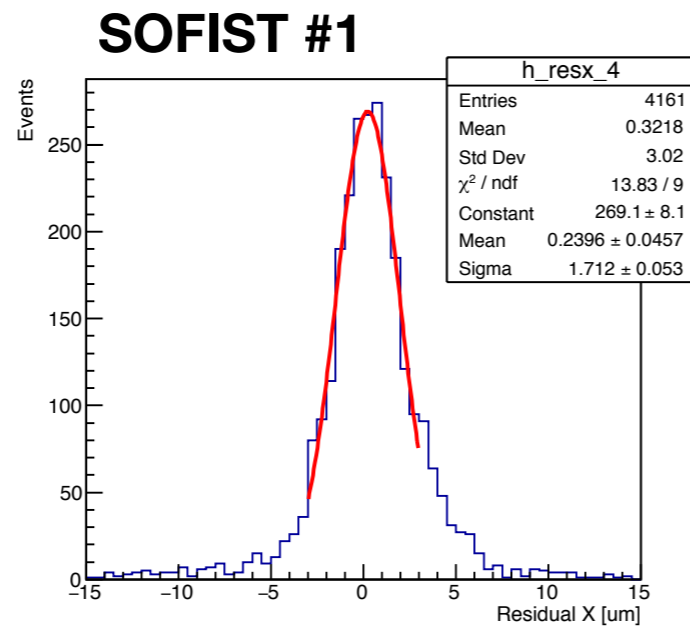
Evaluated by center sensor



- Intrinsic position resolution is expected to be $\sim 0.7 \mu\text{m}$!
- No evaluation systematic error yet **Sub-micron resolution was achieved !**
- Tracking resolution is $\sim 0.5 \mu\text{m}$ **< 1 μm tracking was achieved !!**

SOFIST Residual

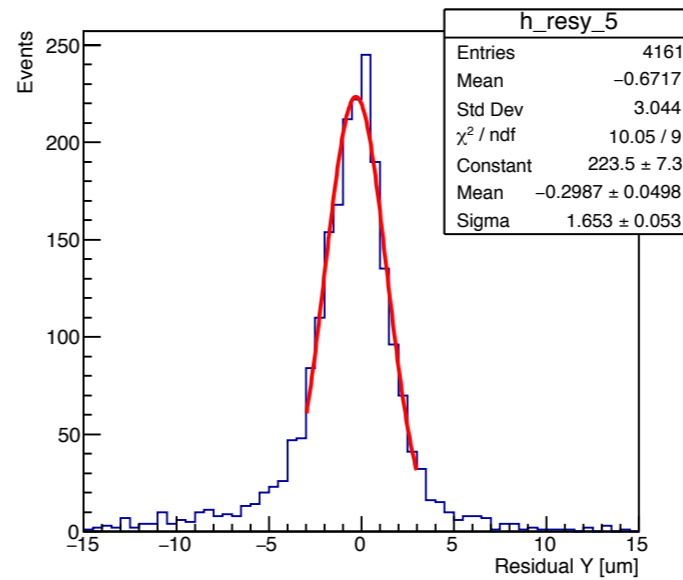
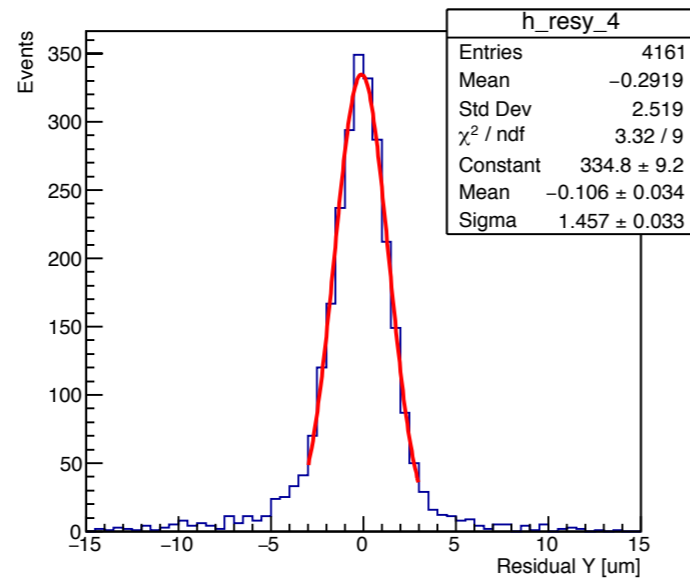
Residual X



1.65 ± 0.05 μm

1.71 ± 0.05 μm

Residual Y



1.46 ± 0.03 μm

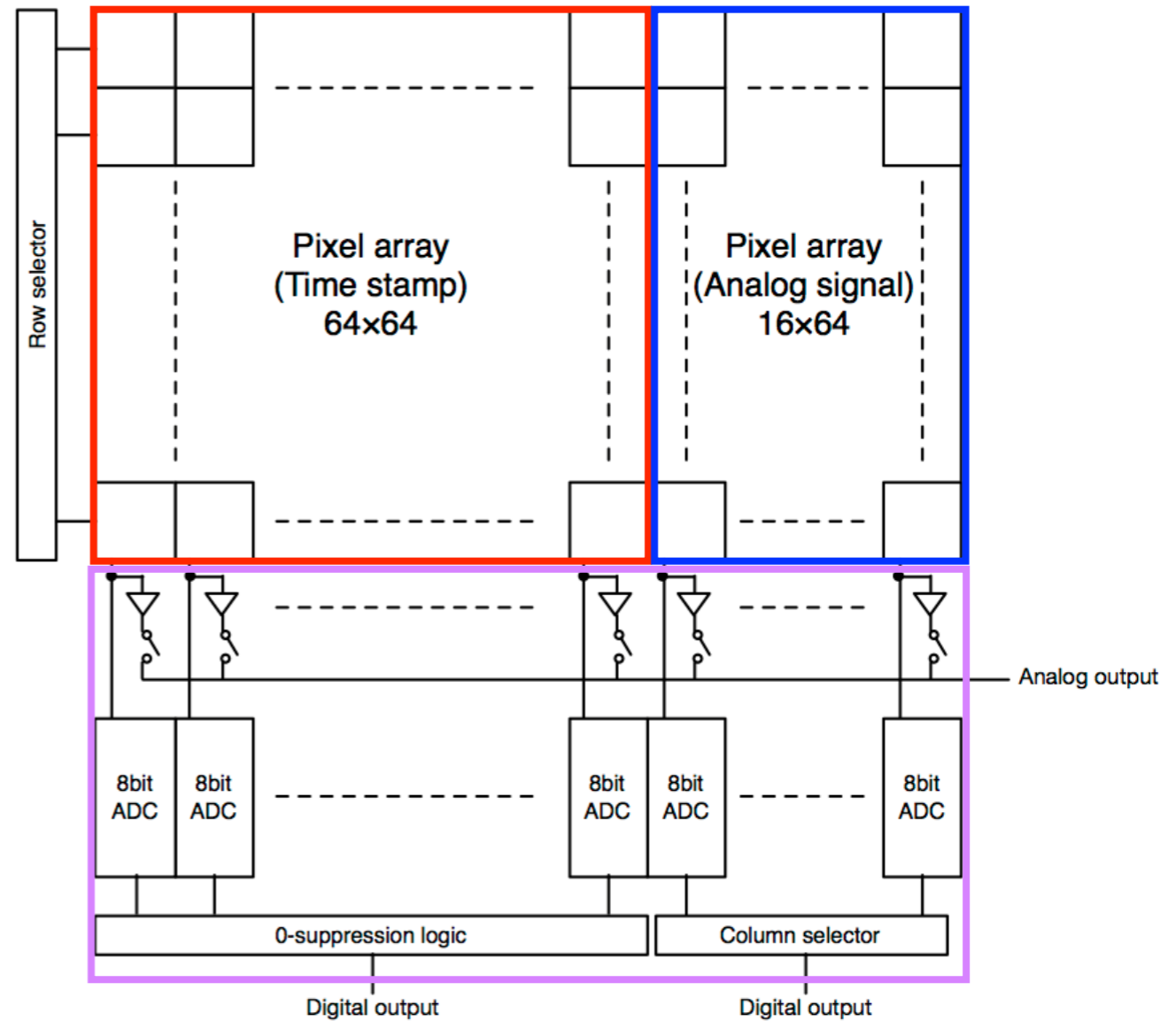
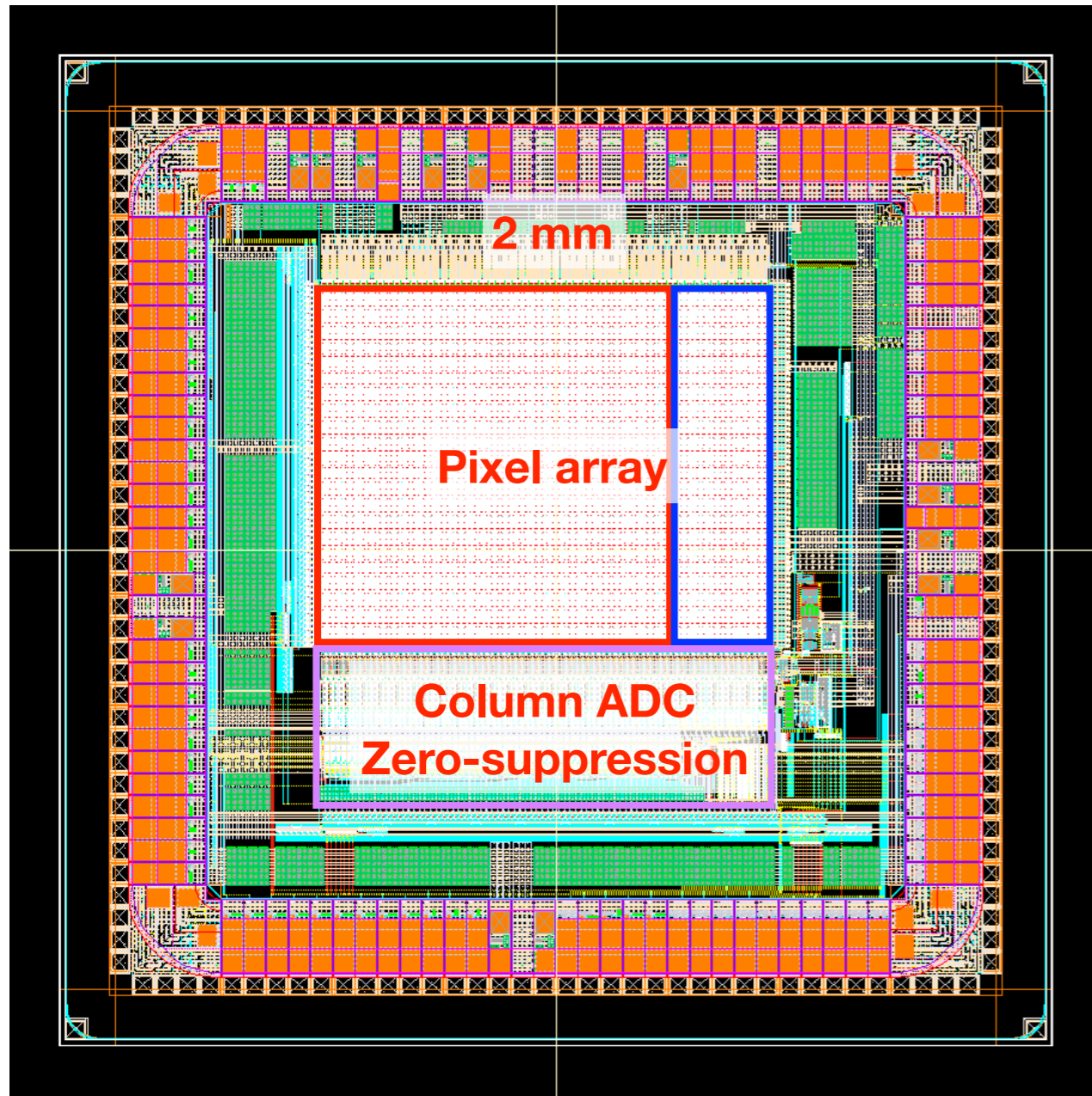
1.65 ± 0.05 μm

SOFIST achieved the residual to ~1.5 μm with 20 × 20 μm² pixel.

SOFIST ver.2

SOFIST ver.2

Wafer: FZ *p*-type



Pixel size: $25 \times 25 \mu\text{m}^2$

Chip size: $4.45 \times 4.45 \text{ mm}^2$

Active area: $2.0 \times 1.6 \text{ mm}^2$ (80×64 pixels)

Wafer: CZ *p*-type, Double SOI, $300 \mu\text{m}$ thickness

SOFIST ver.2

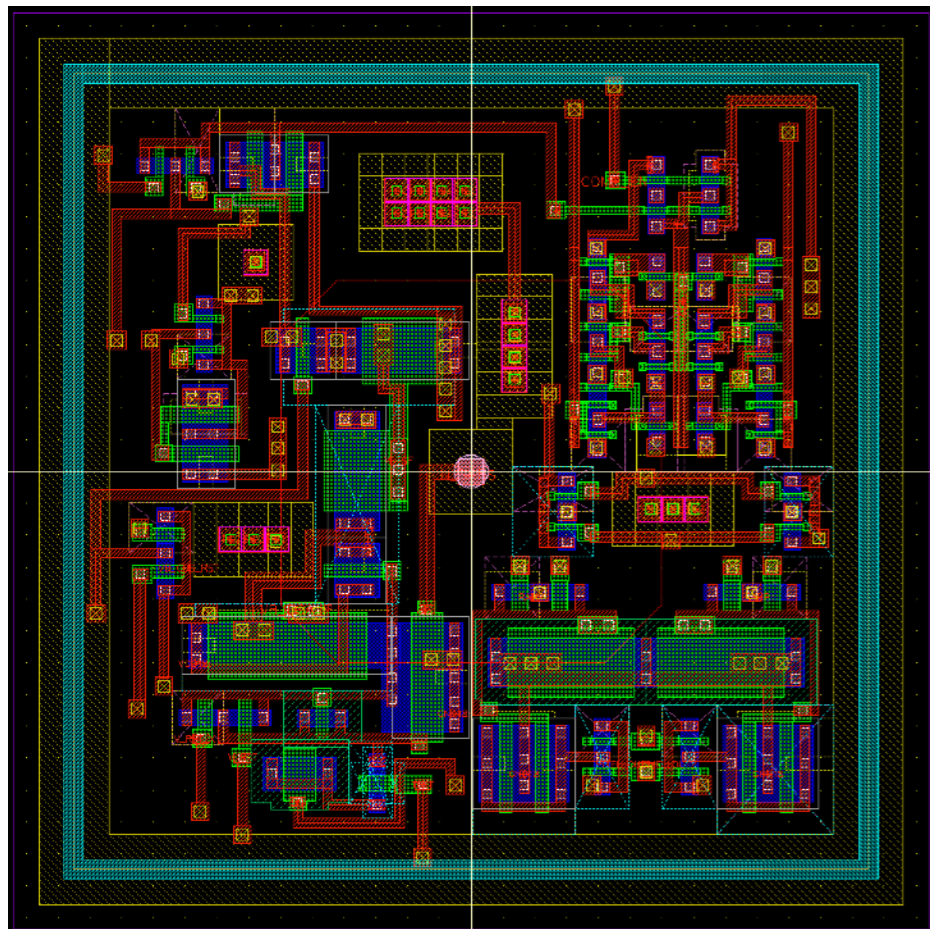
Pixel

- Pre. amplifier (Charge sensitive amplifier)
- Comparator (Chopper inverter)
- Shift register
- Analog signal memories (two memories)
or Time stamp memories (two memories)

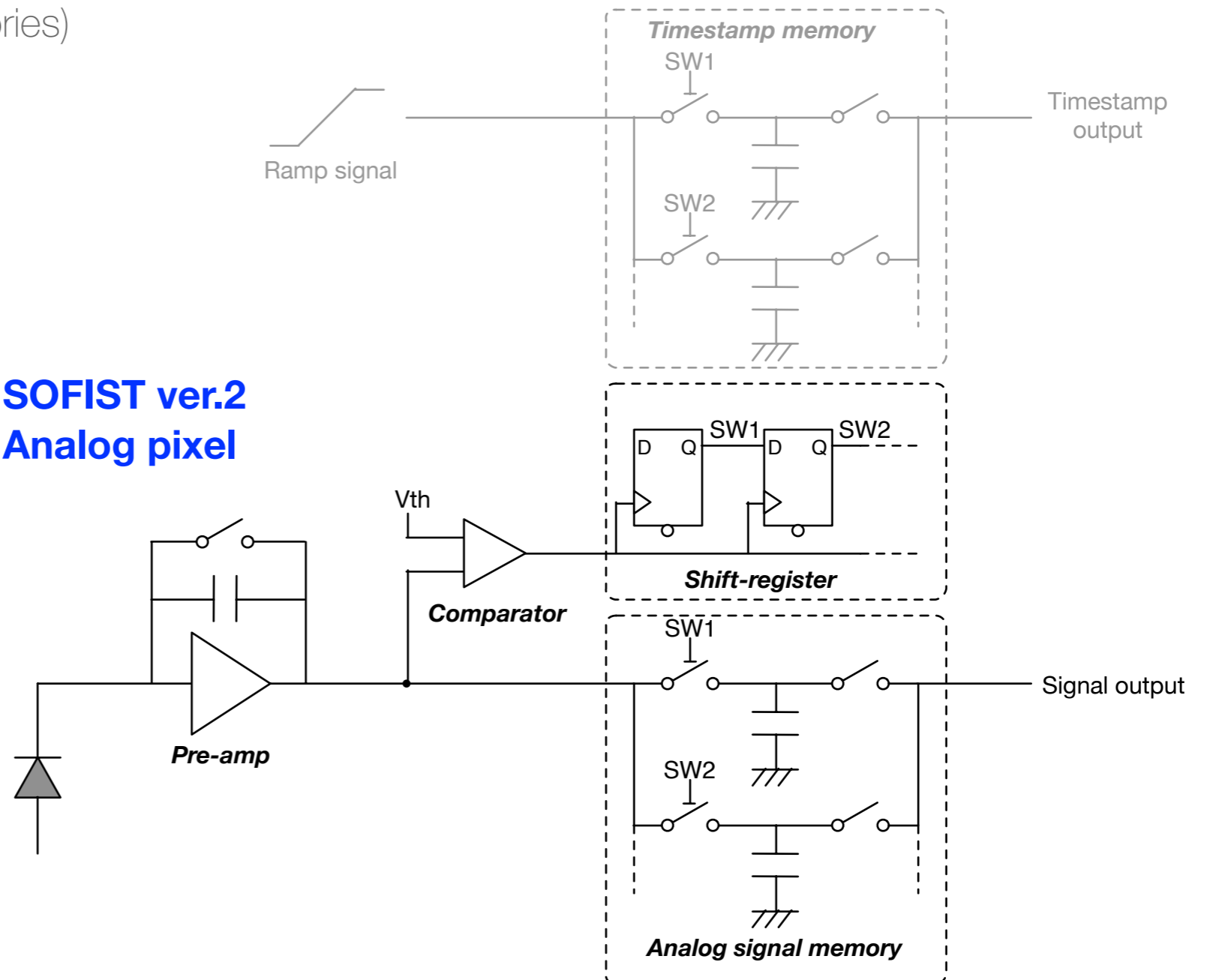
On chip

- 8 bit column ADC
- Zero-suppression logic

Pixel size: $25 \times 25 \mu\text{m}^2$



SOFIST ver.2 Analog pixel



SOFIST ver.2

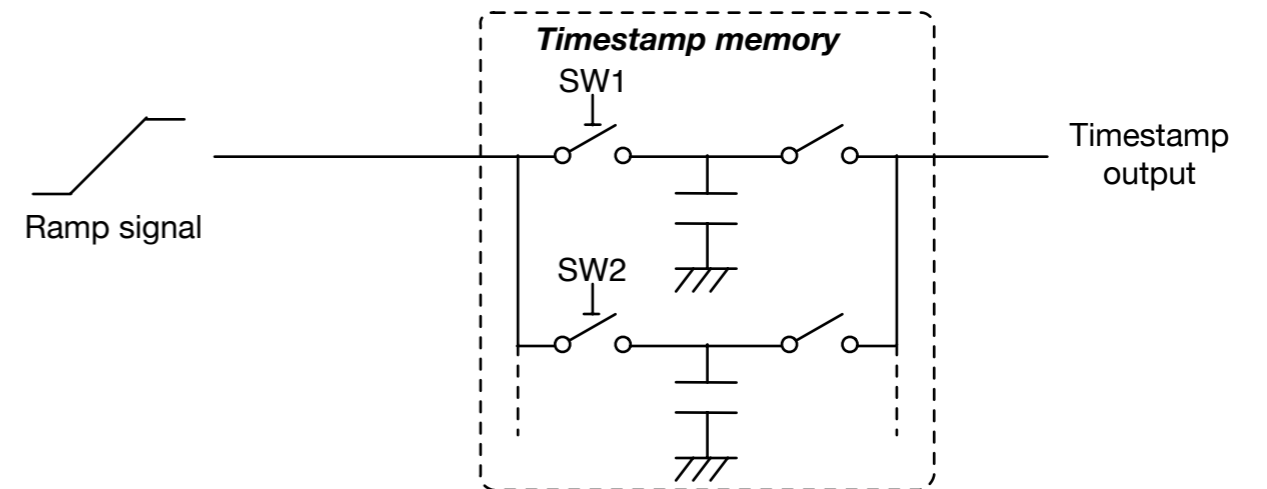
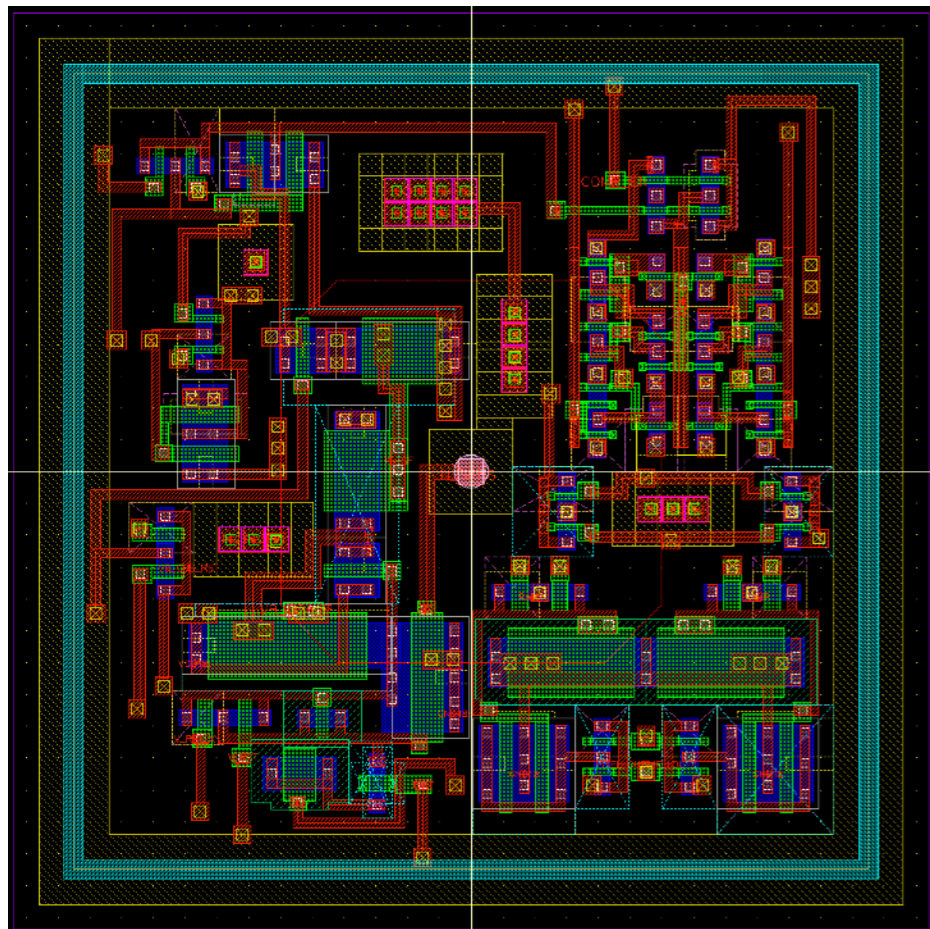
Pixel

- Pre. amplifier (Charge sensitive amplifier)
- Comparator (Chopper inverter)
- Shift register
- Analog signal memories (two memories)
or Time stamp memories (two memories)

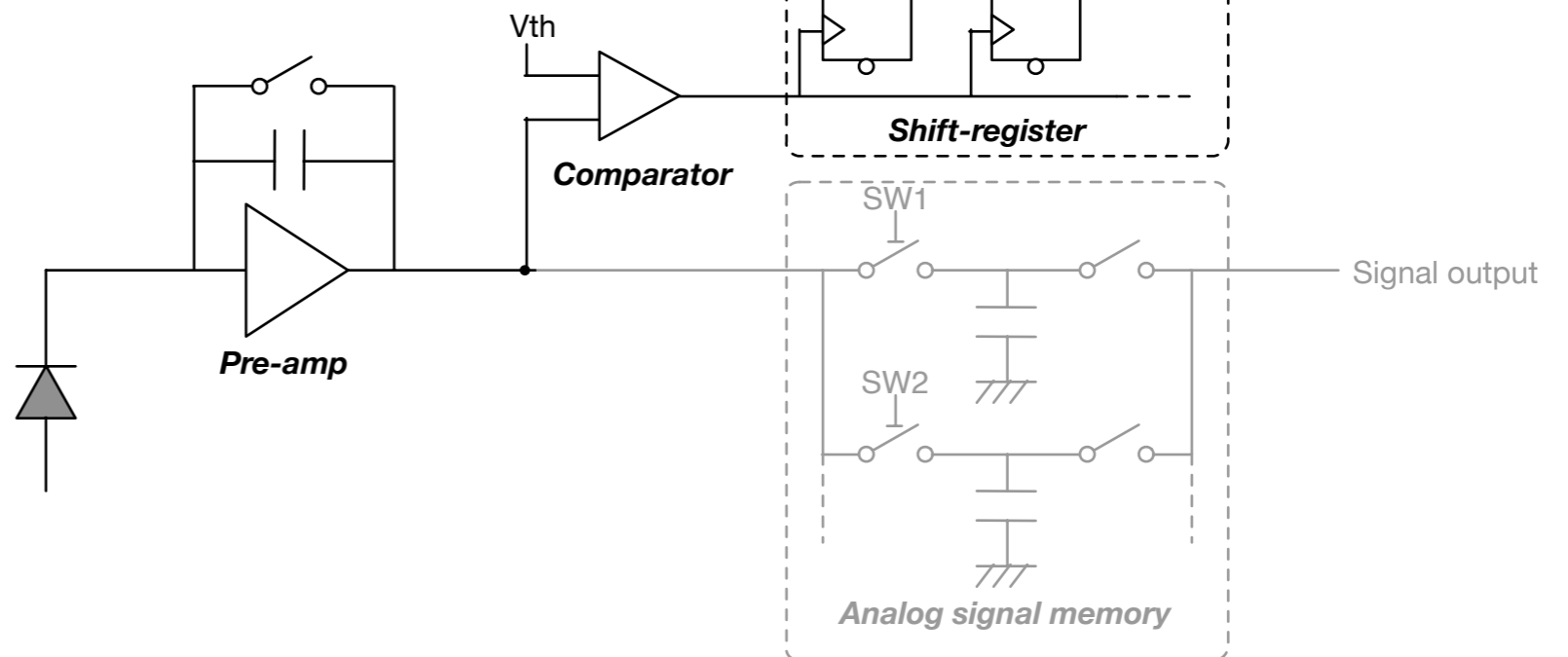
On chip

- 8 bit column ADC
- Zero-suppression logic

Pixel size: $25 \times 25 \mu\text{m}^2$



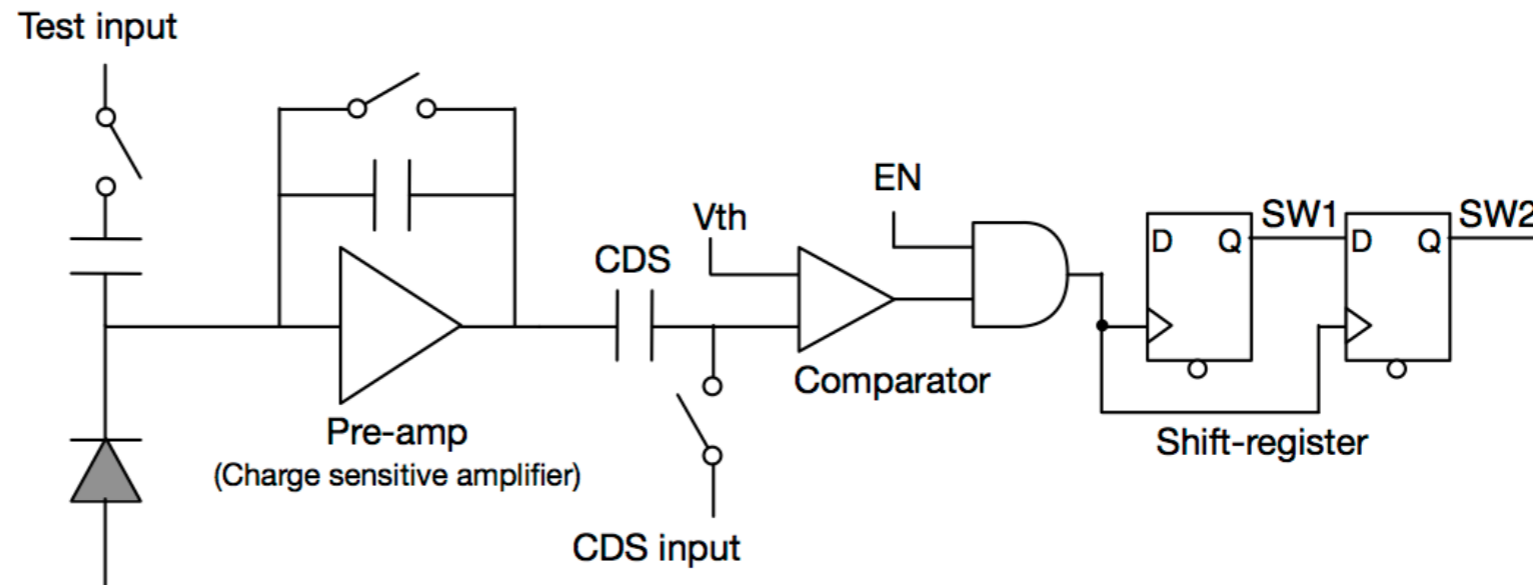
SOFIST ver.2 Time stamp pixel



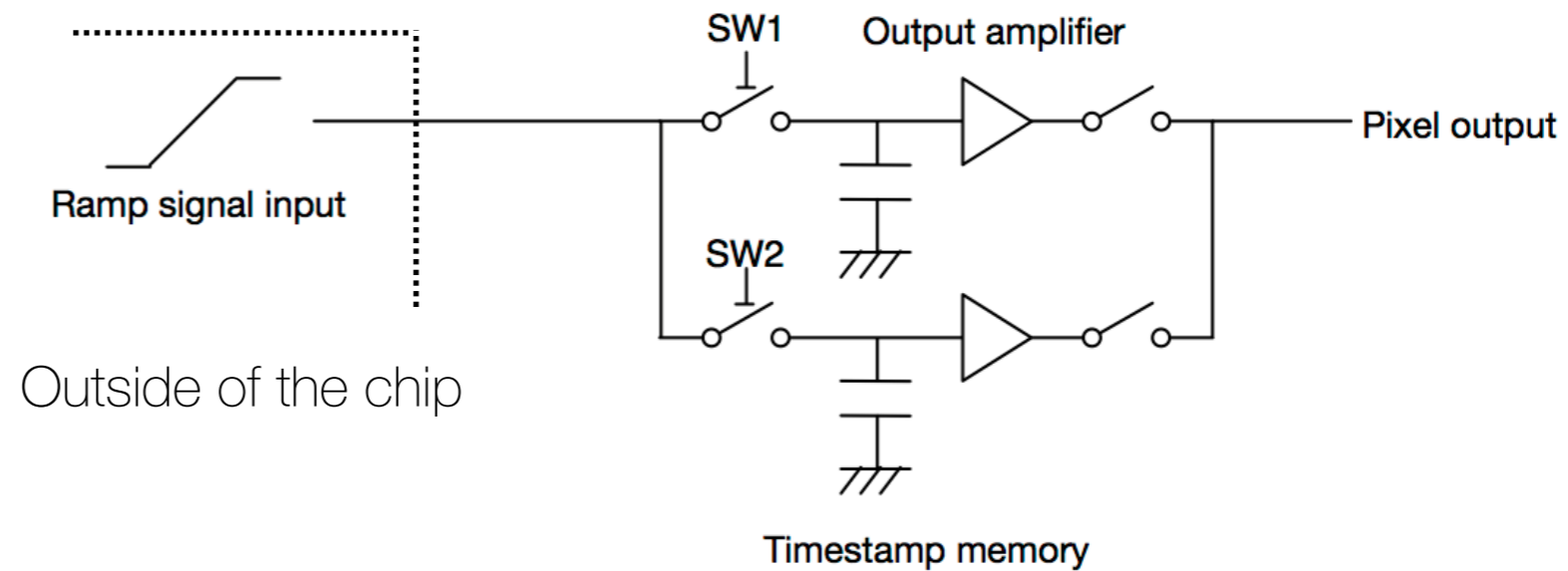
Time Stamp Pixel

Designed by S. Ono (KEK)

- Pre-amplifier
Charge Sensitive Amp.
- Comparator
Chopper Inverter type
- Shift register
D-FF

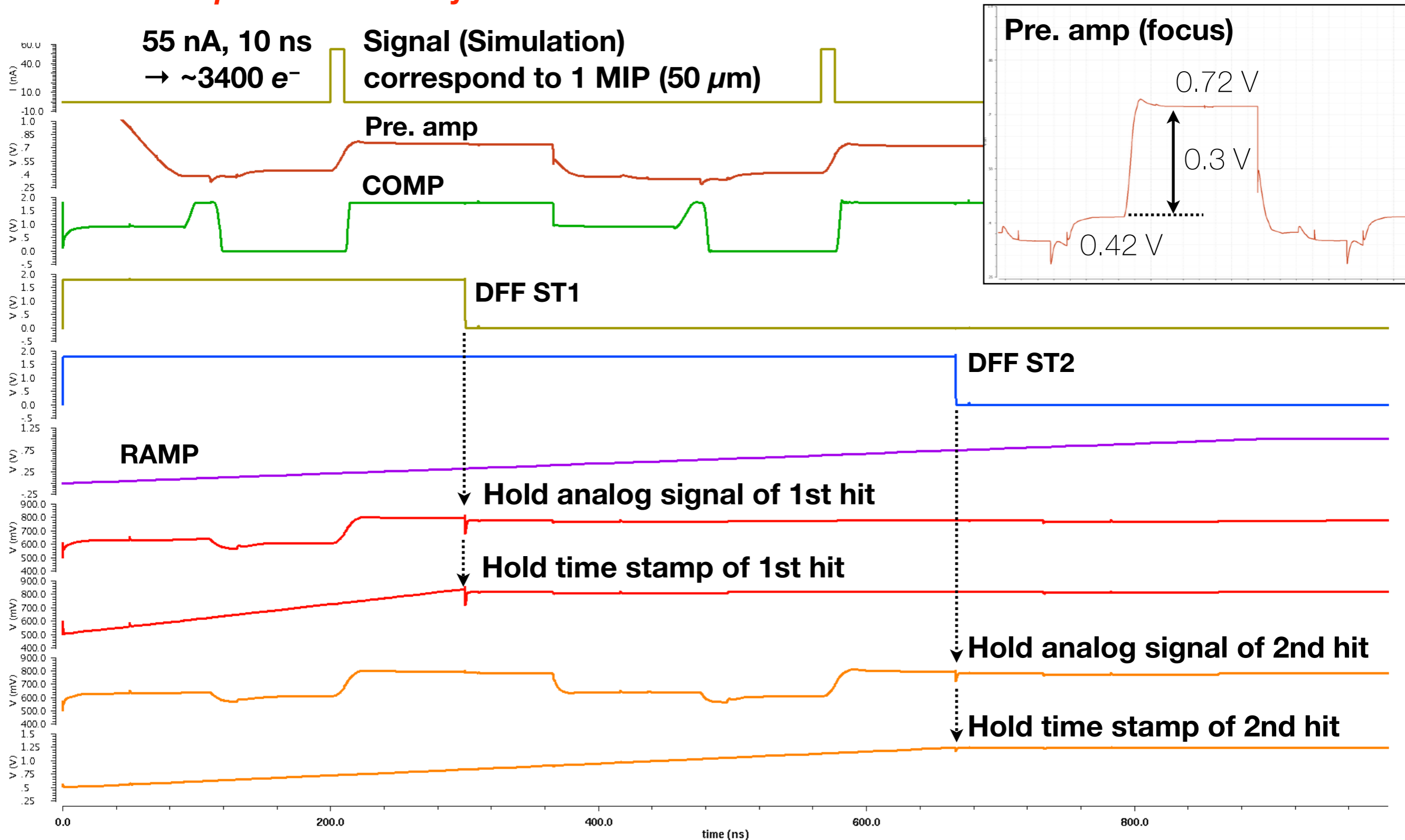


- 1) Input a RAMP waveform.
- 2) Open a store switch (ST1) when a comparator output changes to High.
- 3) Keep the voltage of RAMP to the time stamp memory as a time stamp.
- 4) in the same way for 2nd hit.



Time Stamp and Analog Pixel

Simulation of 1 μs transient analysis



SOFIST ver.3 & 4

SOFIST ver.3

Pixel

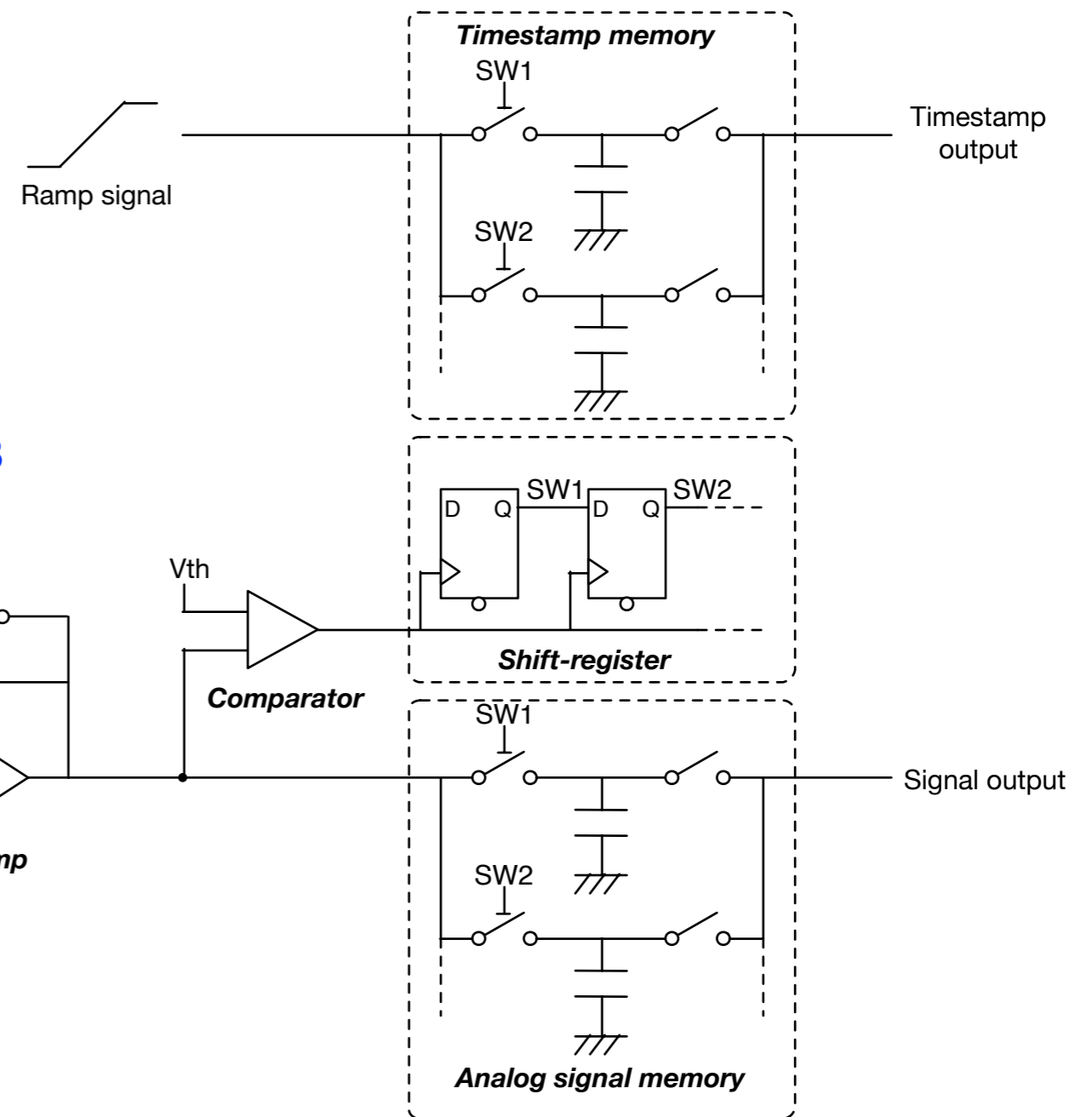
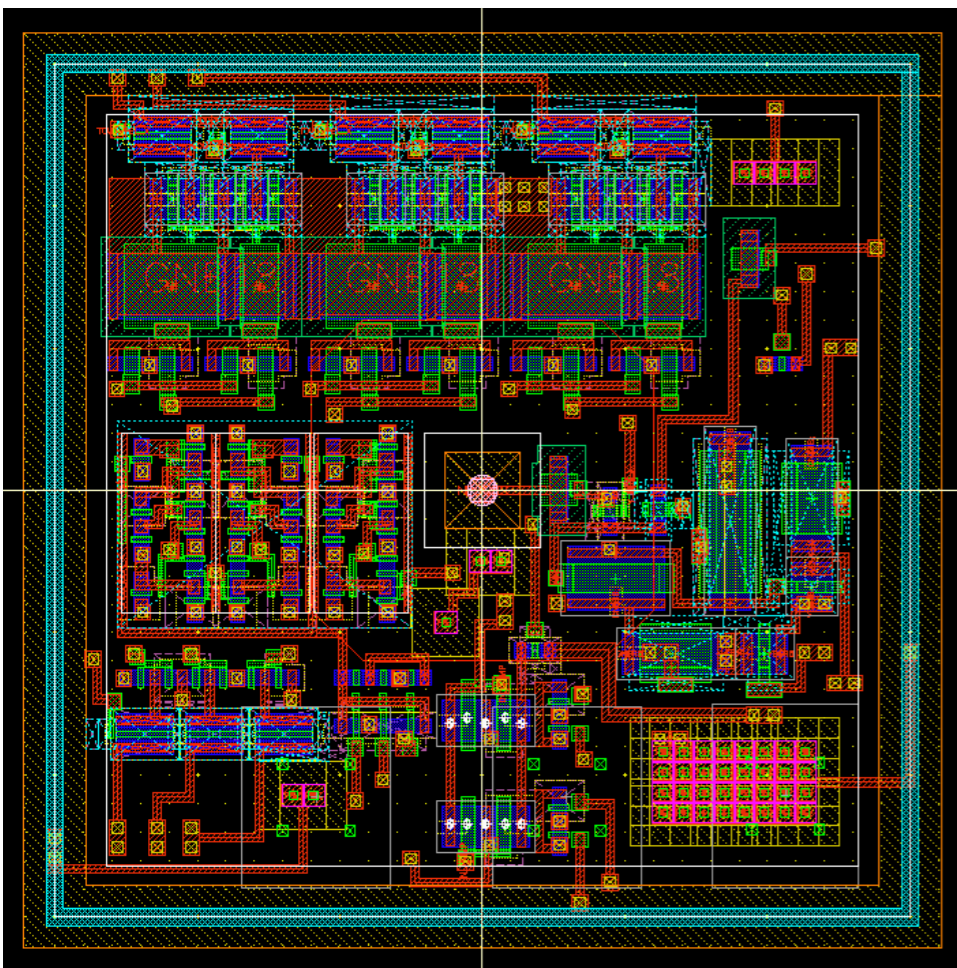
- Pre. amplifier (Charge sensitive amplifier)
- Comparator (Chopper inverter)
- Shift register
- Analog signal memories (three memories)
- Time stamp memories (three memories)

On chip

8 bit column ADC

Pixel size: $30 \times 30 \mu\text{m}^2$

SOFIST ver.3 is still under designed.
We are going to submit in June 2017.



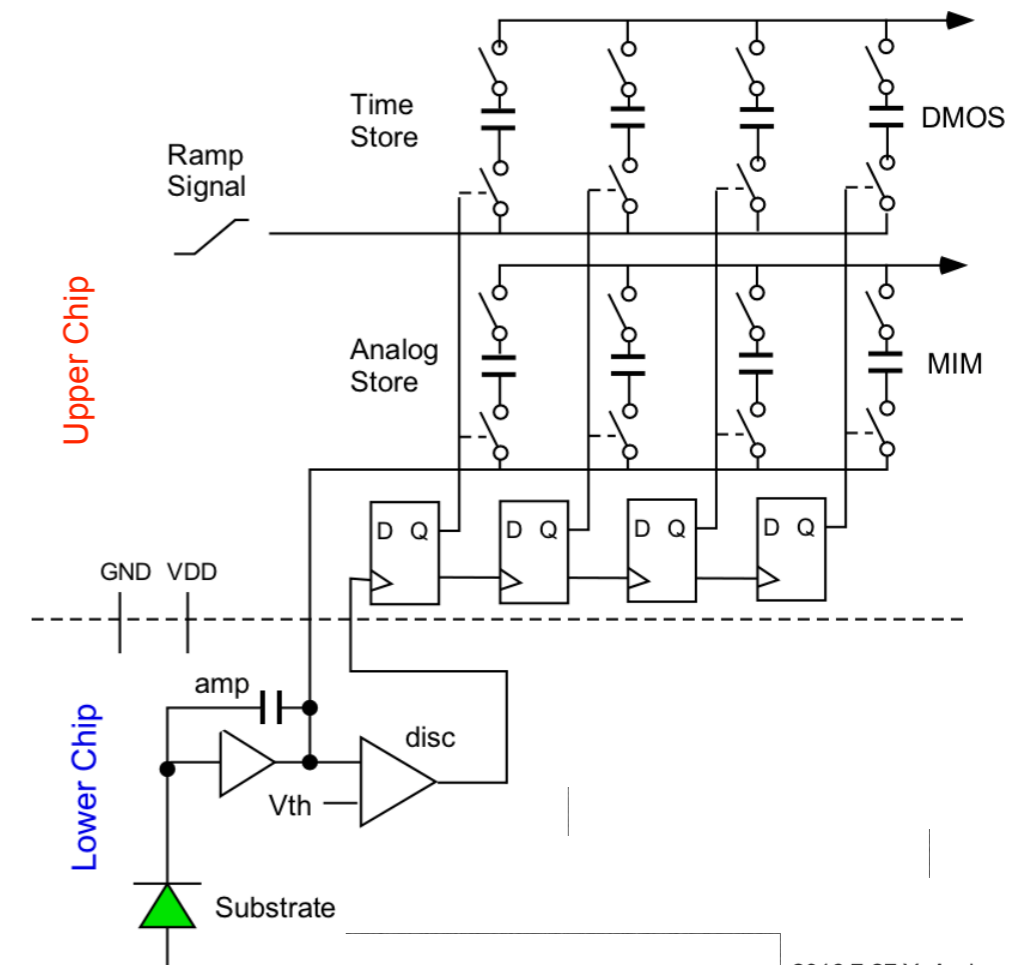
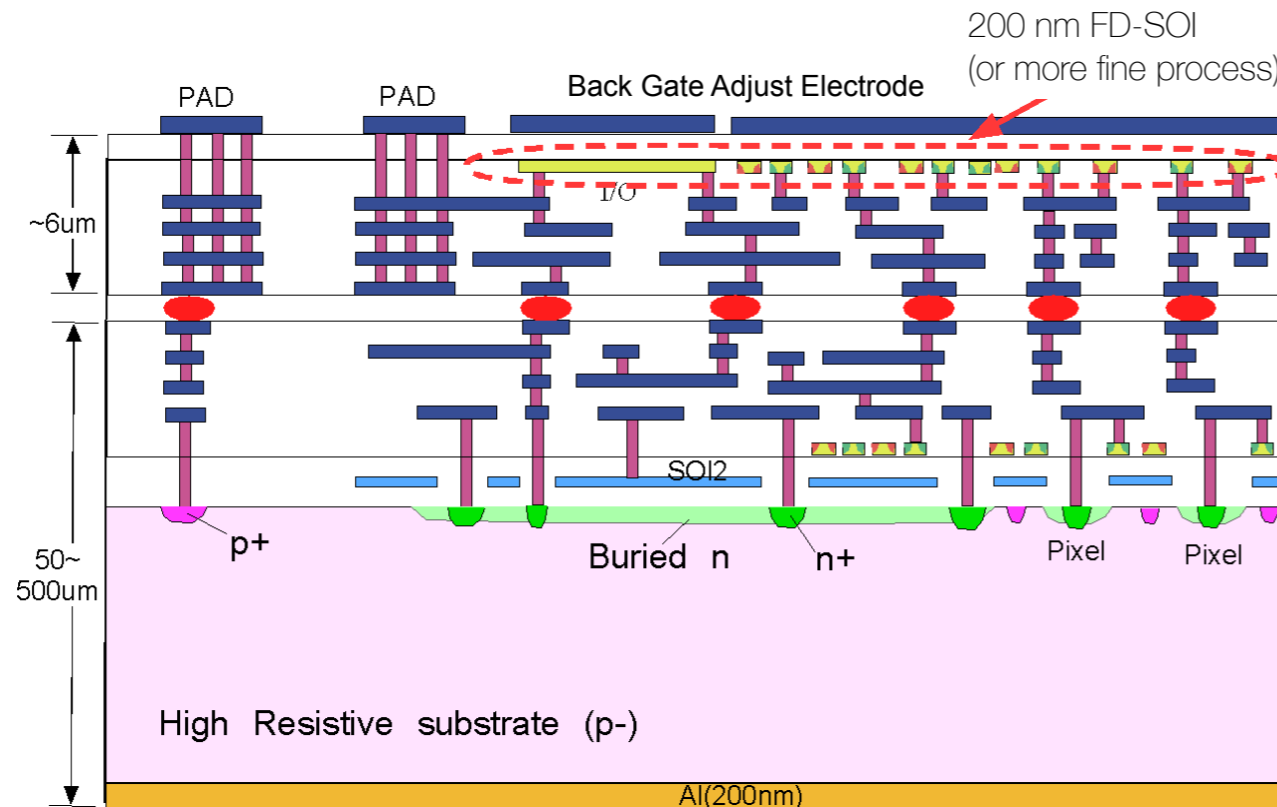
All the functions are implemented in a pixel but larger pixel size.

SOFIST ver.4 (3D)

3D integration of SOI sensor

for implementation of complex circuit within $20 \times 20 \mu\text{m}^2$ pixel.

Upper Chip
Lower Chip
Sensor



2016.7.27 Y. Arai

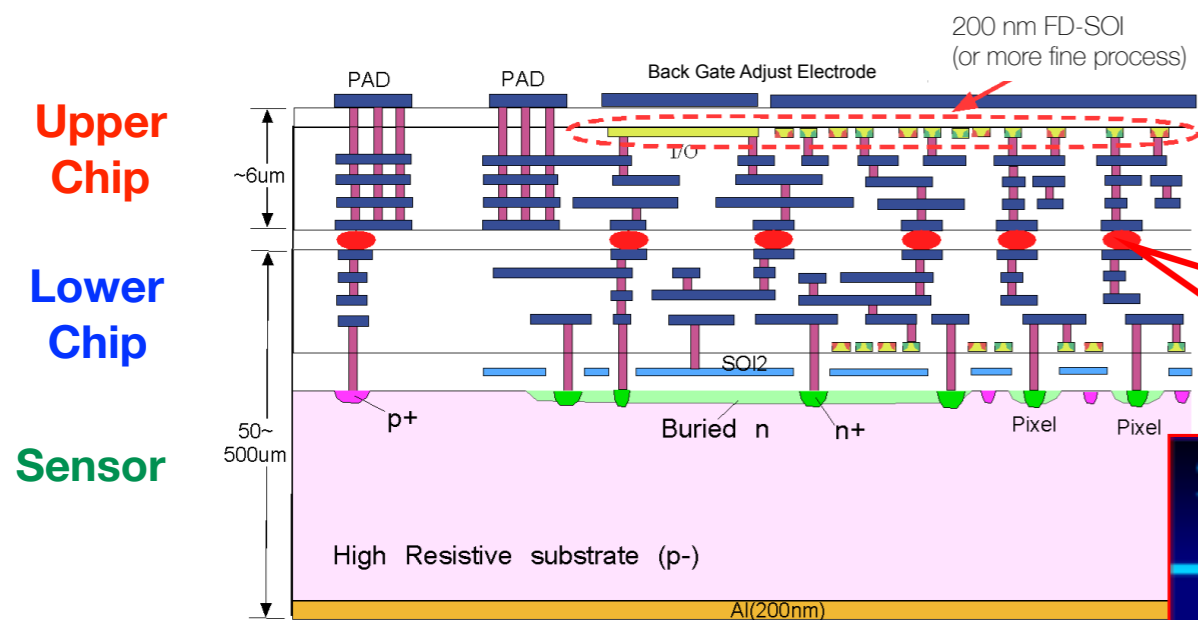
Upper chip: Digital part (D-FF, analog memories and time stamp memories up to 3 or more hits)

Lower chip: Analog part (pre.amp and comparator)

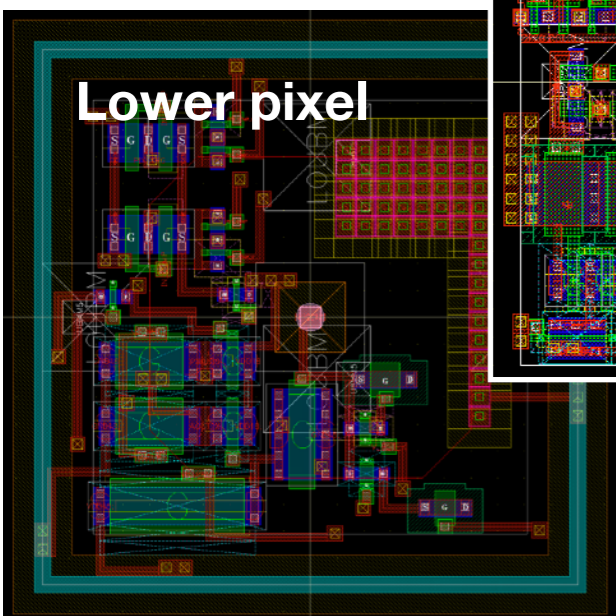
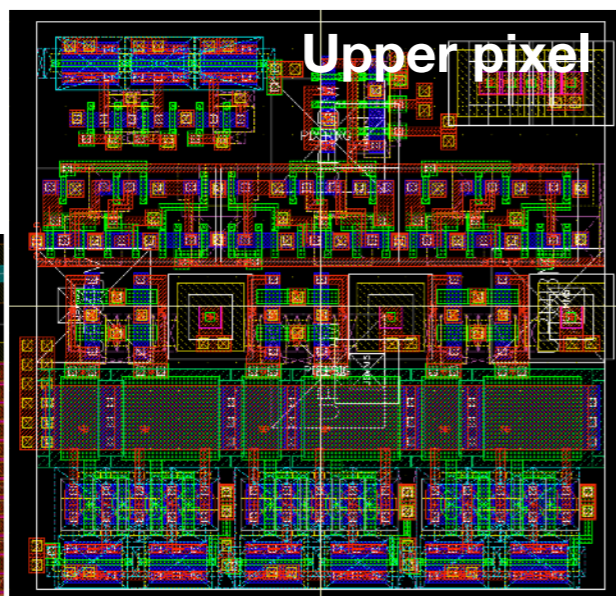
SOFIST 3D

3D integration of SOI sensor

→ Connect the upper and lower chip by Au cone bump (2.5 μmφ).



Tohoku MicroTec Co., Ltd.
<http://www.t-microtec.com>



T-Micro
2.5/5.0μmφ Au Cone Bump

2.5μmφ

5.0μmφ

TEG cross section

Pixel2014 © Niagara Falls Sept. 4, 2014
10
T-Micro/Motoyoshi

Summary

We are designing and developing a monolithic type pixel detector with SOI technology for the ILC vertex detector (SOFIST).

SOFIST ver.1

We evaluated S/N and position resolution by using 120 GeV proton beam at Fermilab beam test facility in Jan. 2017.

- S/N ~360 at HV = 130 V for 500 μm thickness sensor.
- Position resolution (residual) ~1.5 μm .

SOFIST ver.2

Chip have already delivered to KEK in Jan. 2017, and we are preparing DAQ.

We will evaluate

- Time stamp function for multiple hit (up to two hits).
- Thinned sensor (75 μm).

SOFIST ver.3 and 4

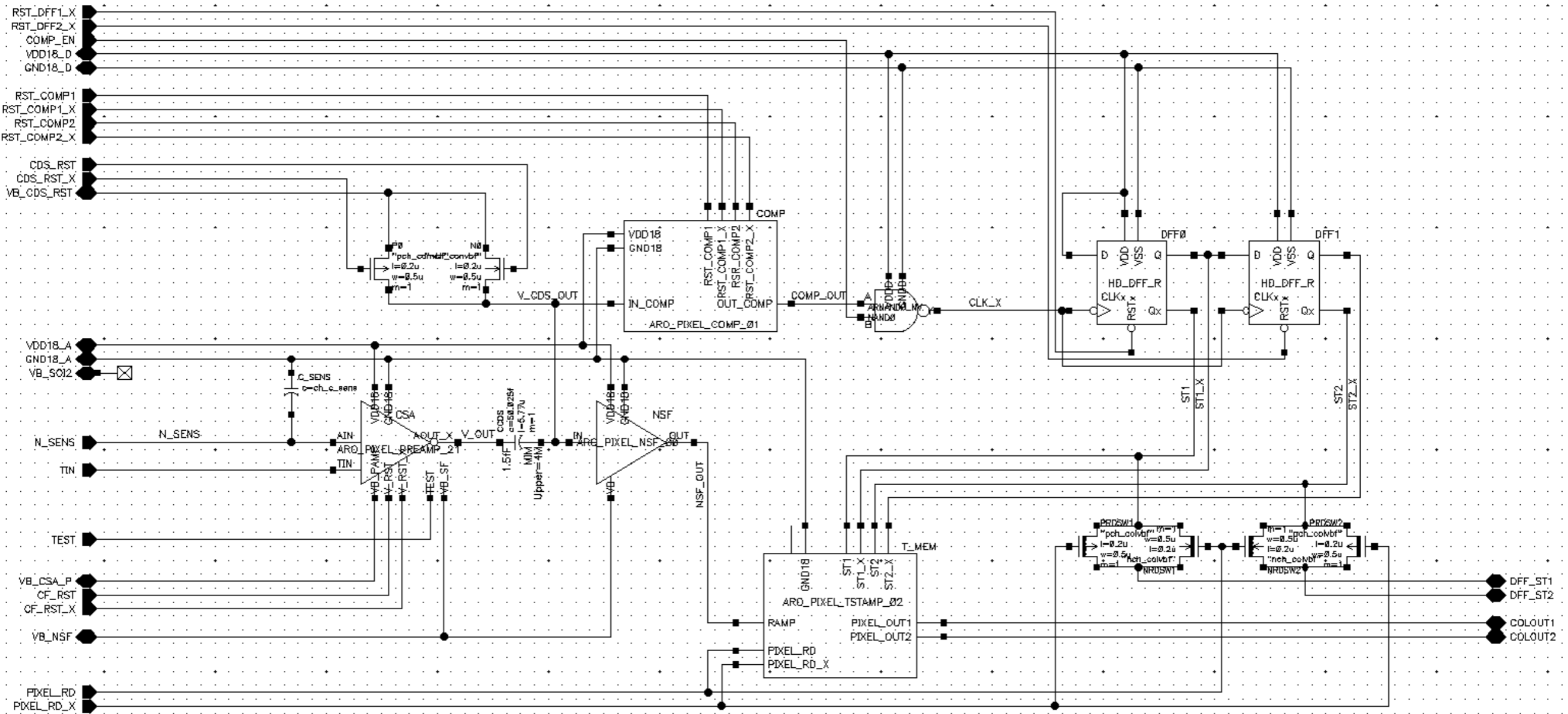
ver.3 and 4 chips are still under designing (submit in June 2017).

ver.3: all necessary functions are implemented in a single pixel but 30 \times 30 μm^2 pixel size.

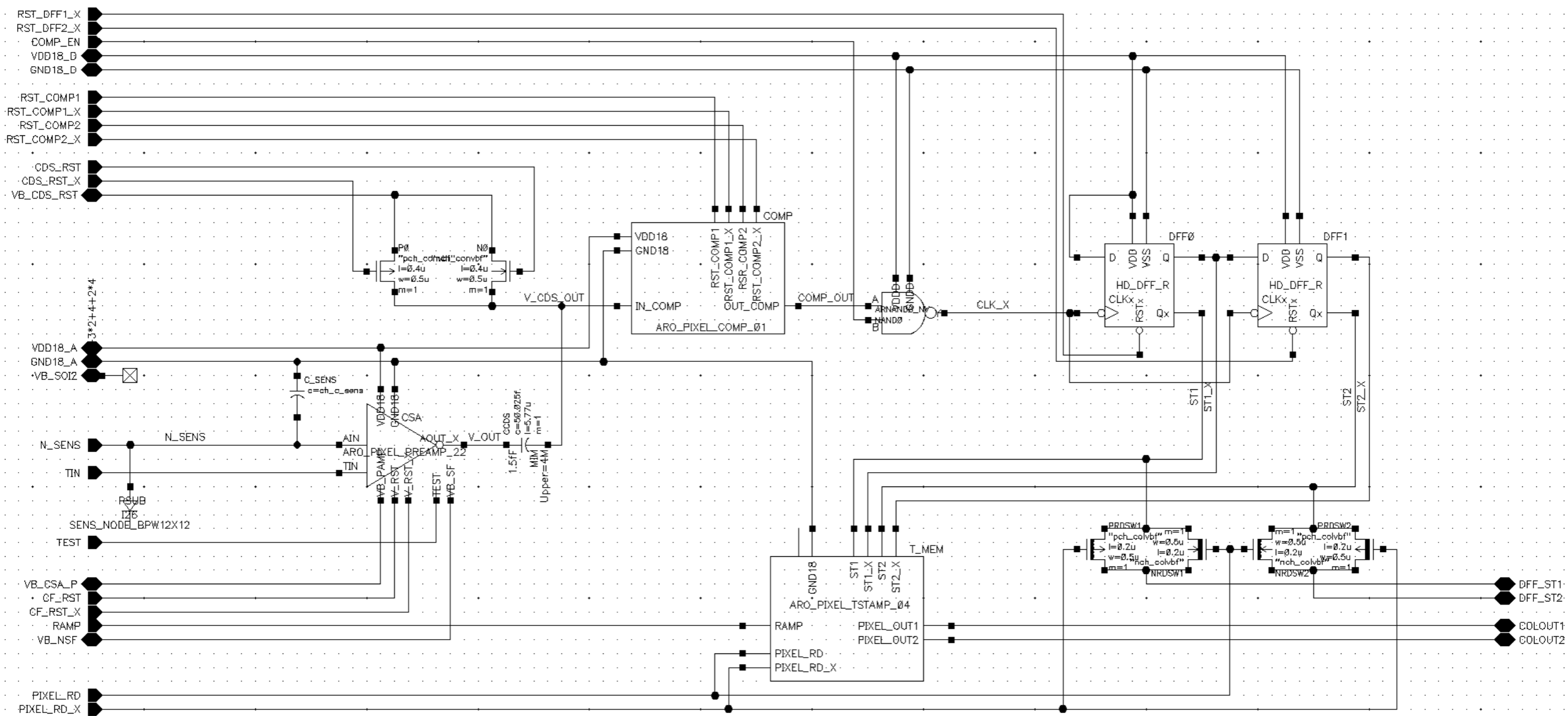
ver.4: all necessary functions are implemented in 20 \times 20 μm^2 pixel with 3D integration technology (Au cone bump).

Backup

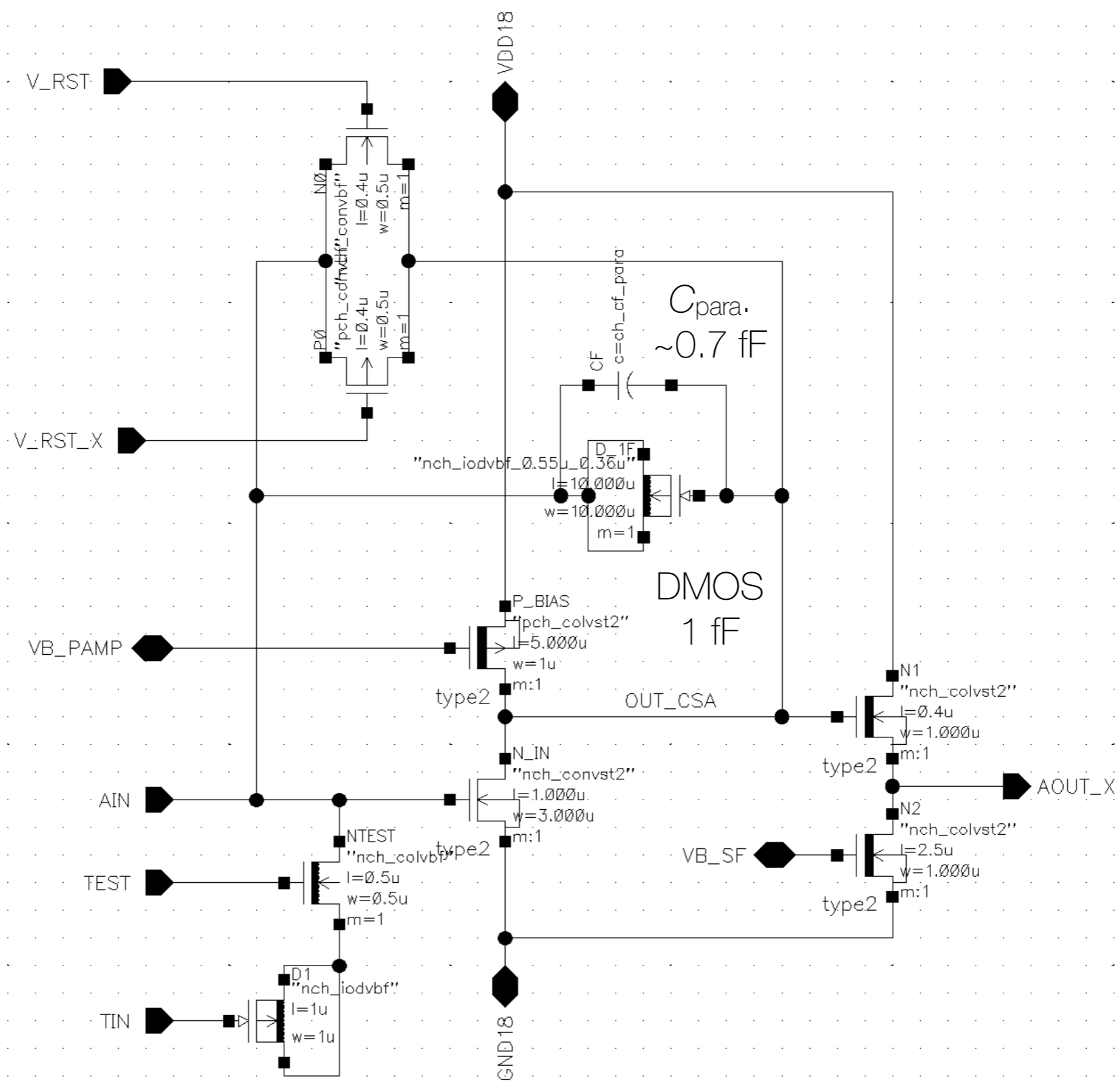
Analog Pixel



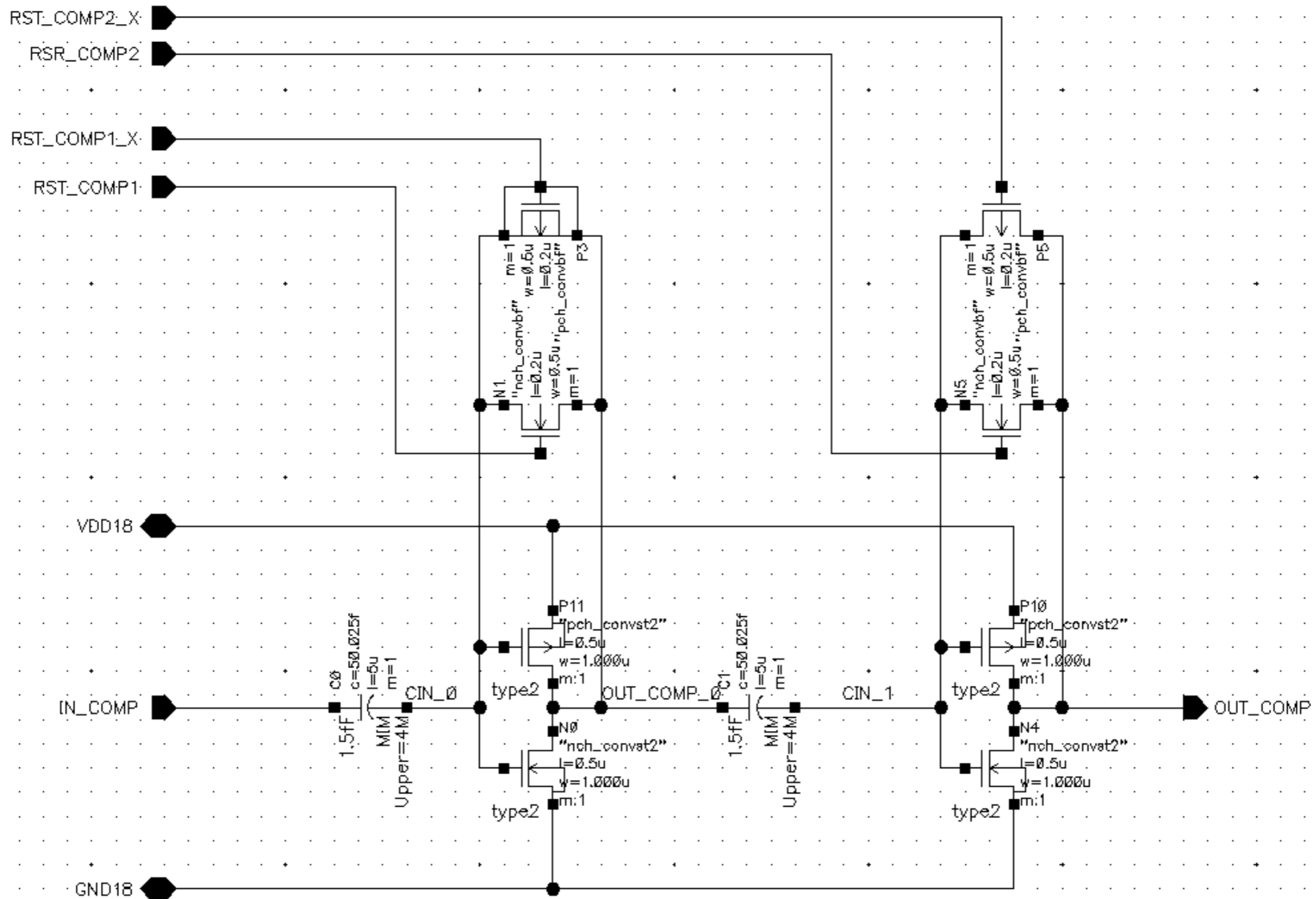
Time Stamp Pixel



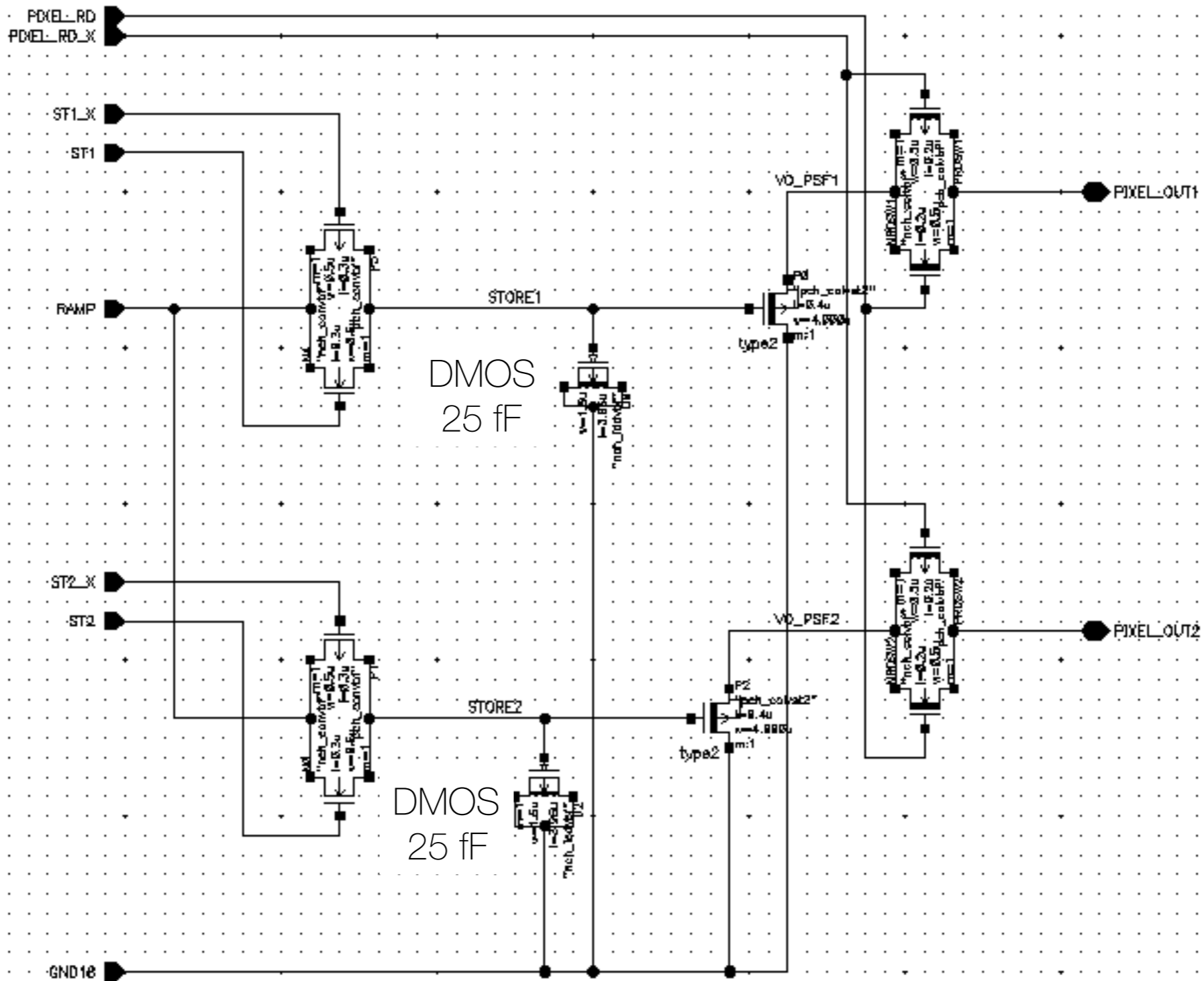
Pre-amplifier



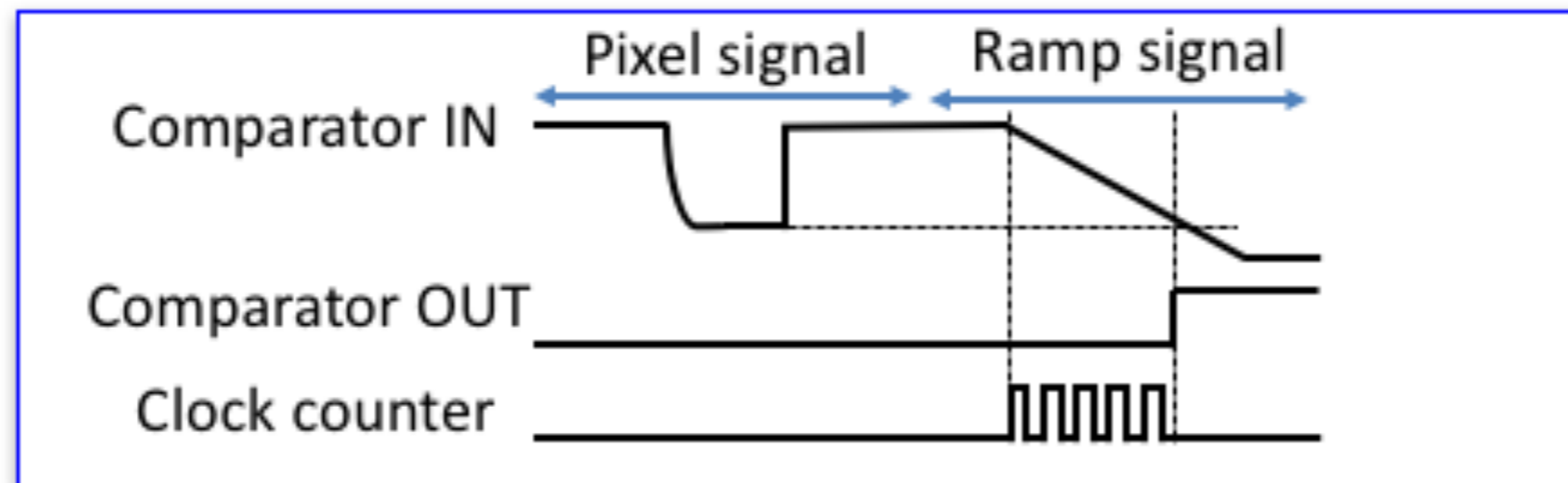
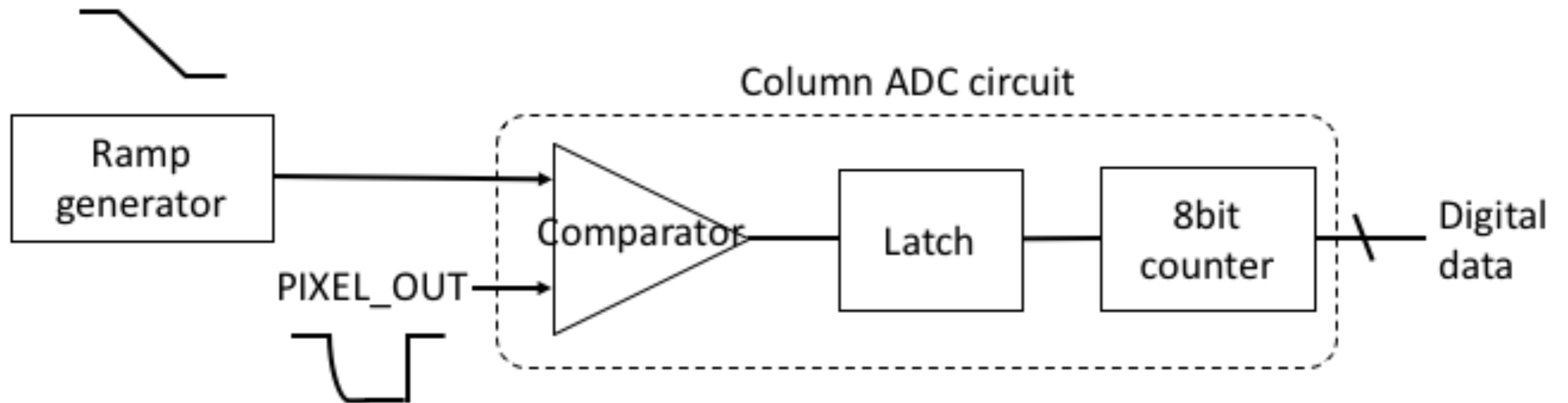
Comparator



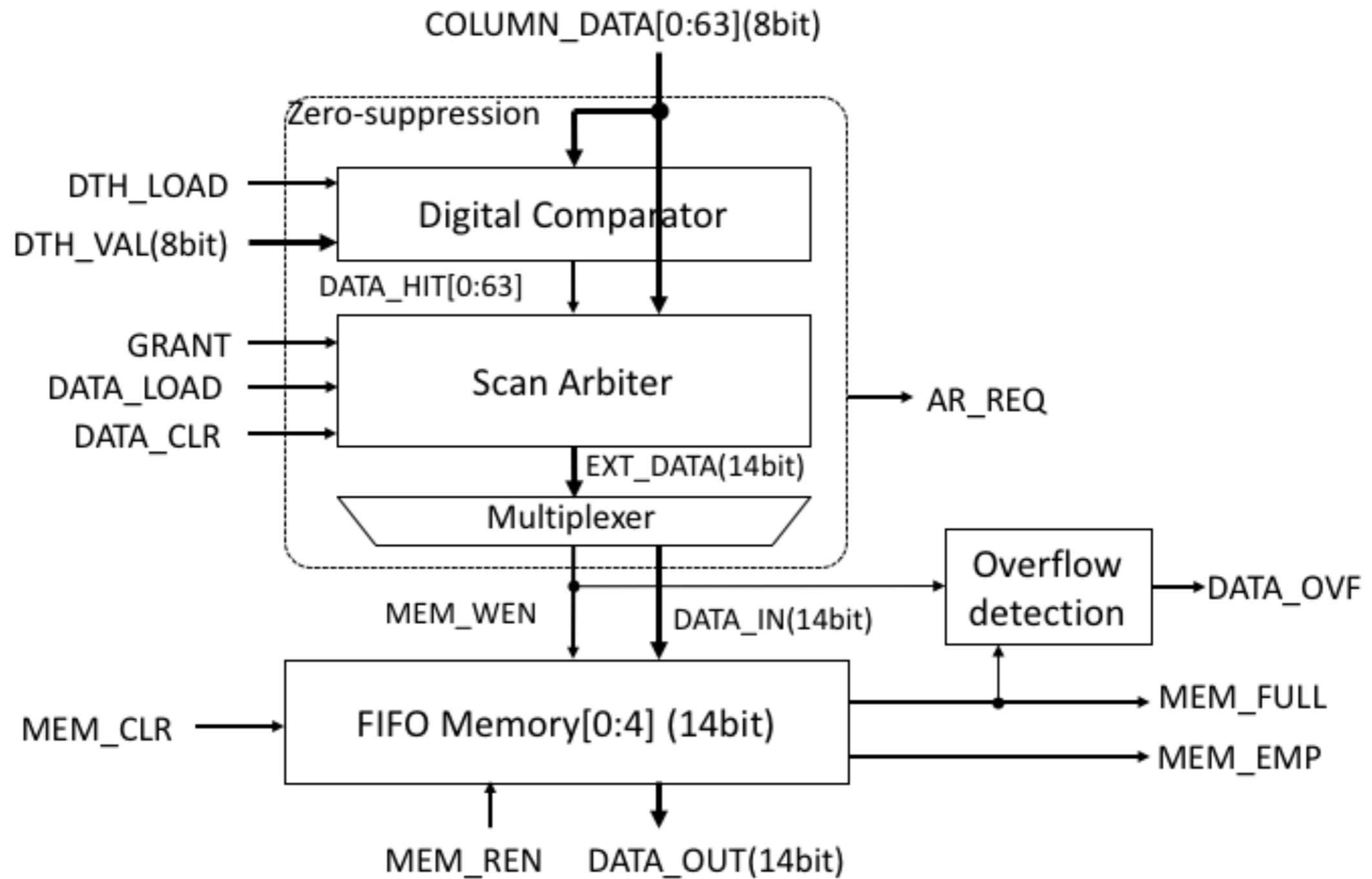
Memory



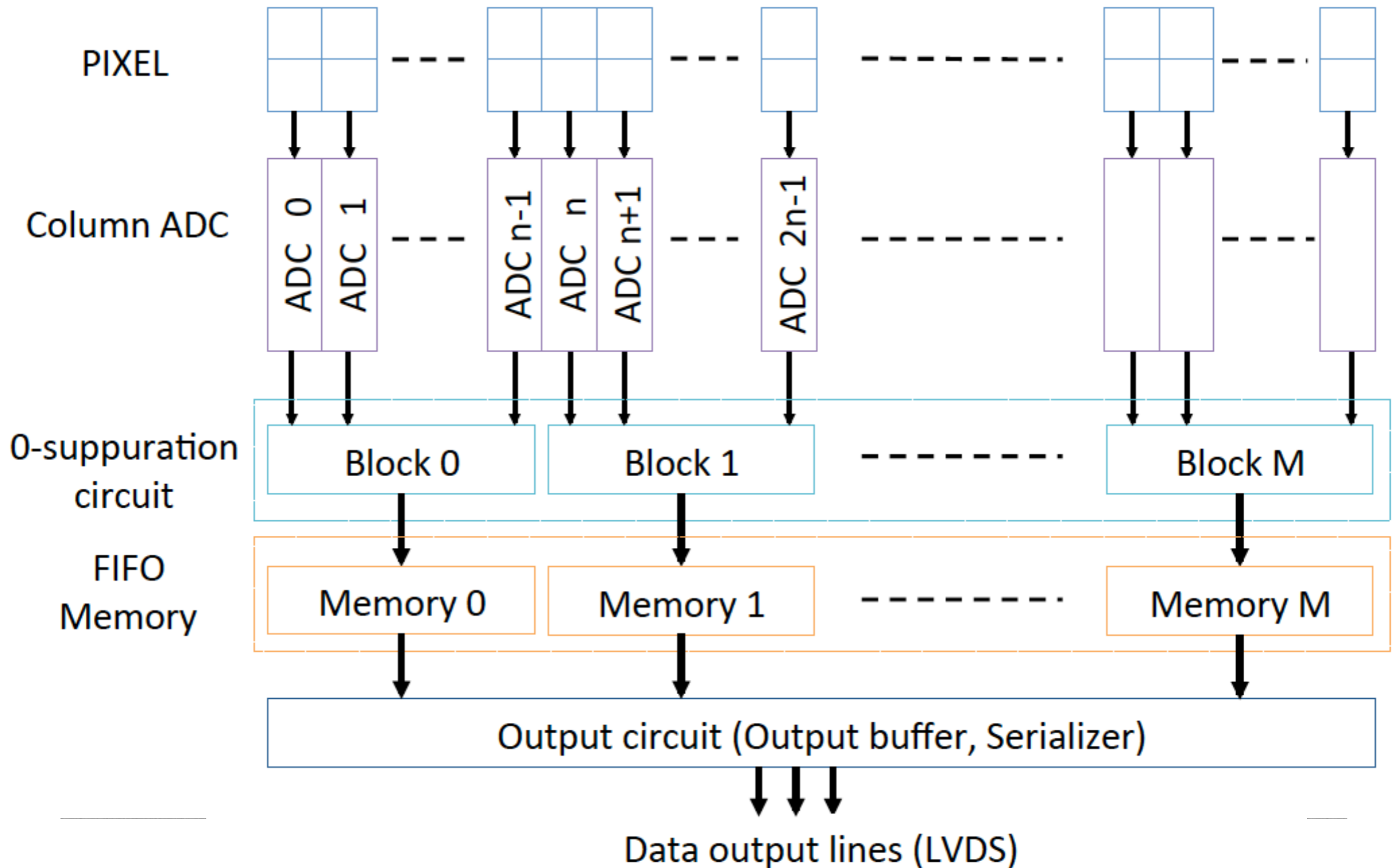
Column ADC



0-suppression Logic

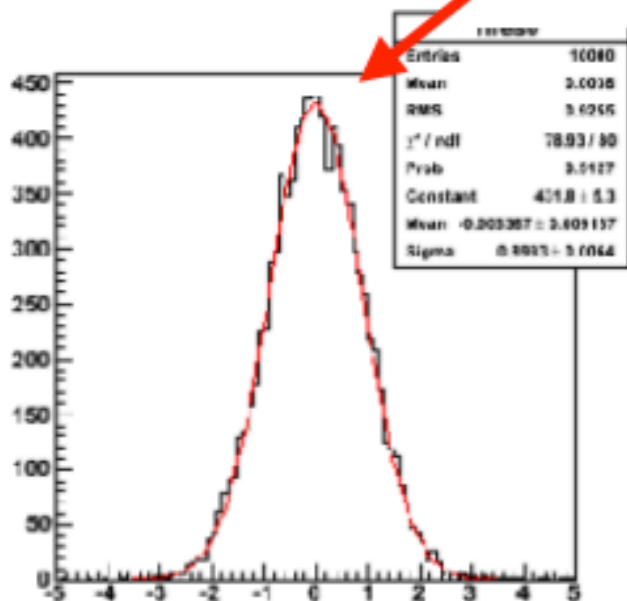
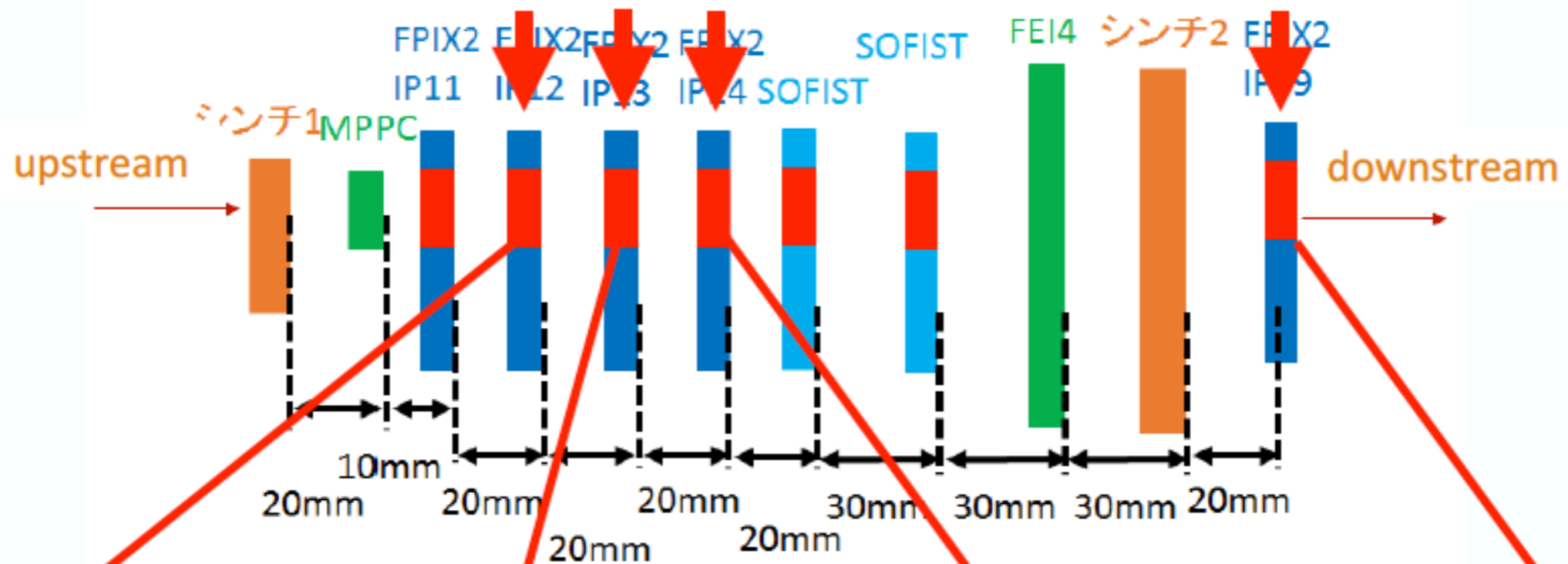


Data Flow

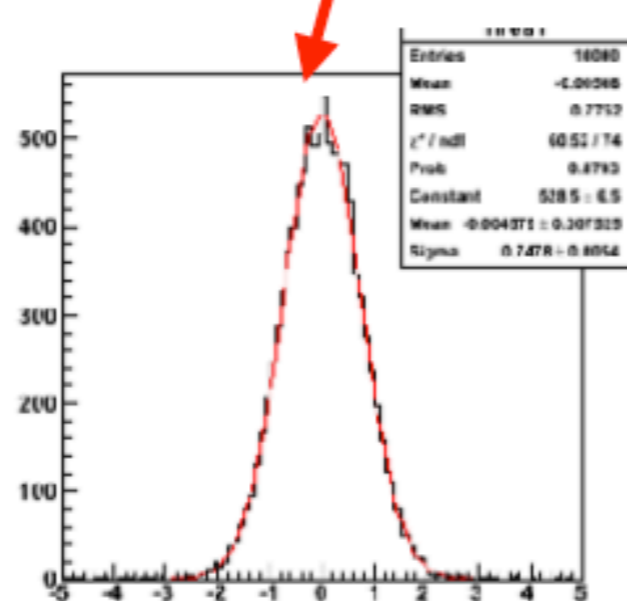


Residual distribution by MC w/ intrinsic resolution=0.6 um

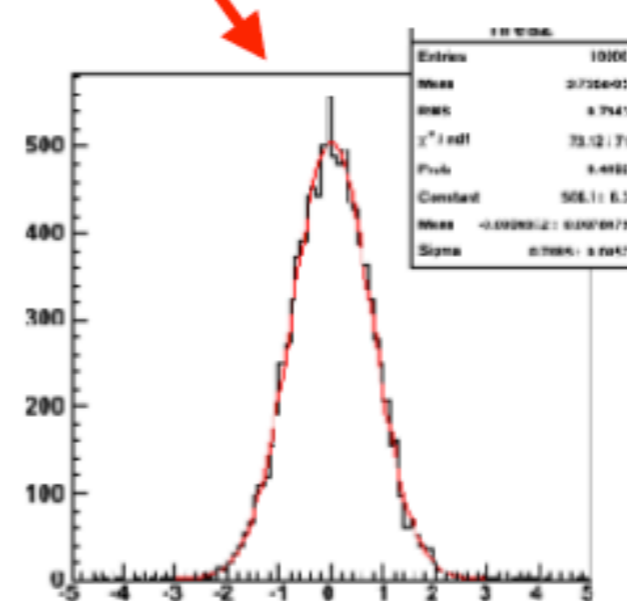
- Tracking by straight line : $y = a_y * z + b_y$



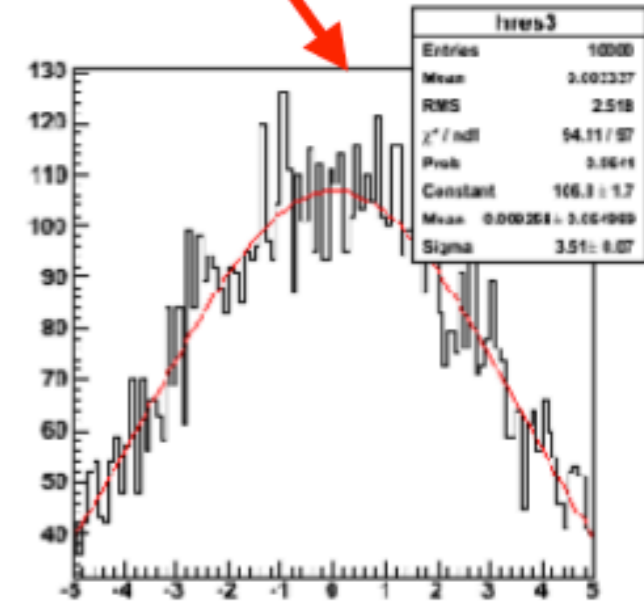
$\sigma = 0.90 \text{ um}$



$\sigma = 0.75 \text{ um}$



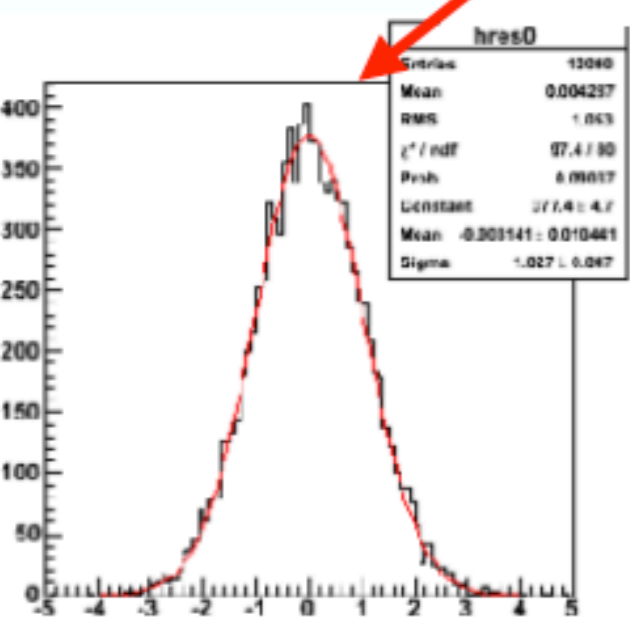
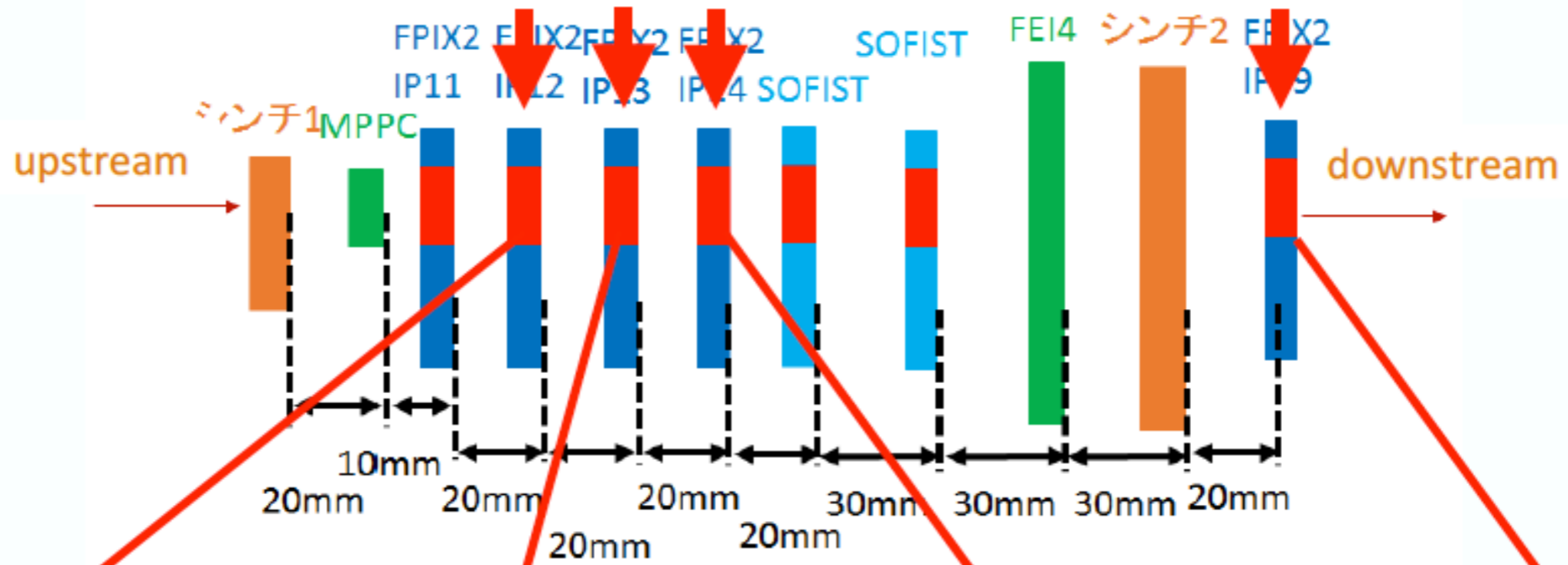
$\sigma = 0.77 \text{ um}$



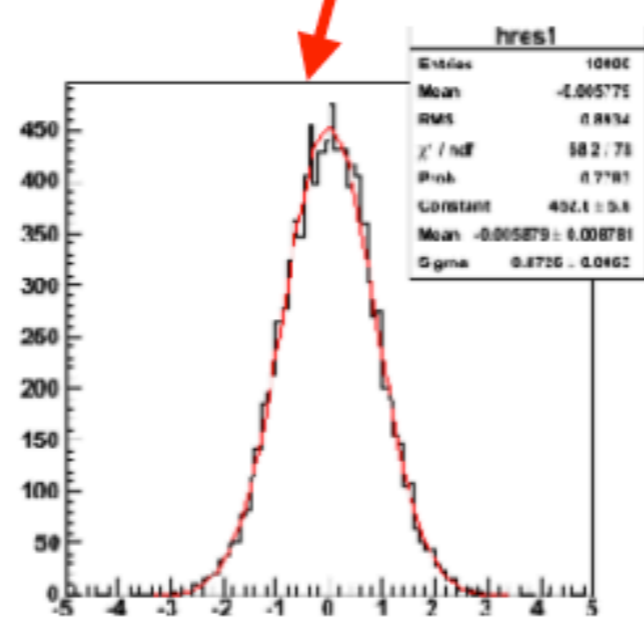
$\sigma = 3.51 \text{ um}$

Residual distribution by MC w/ intrinsic resolution=0.7 um

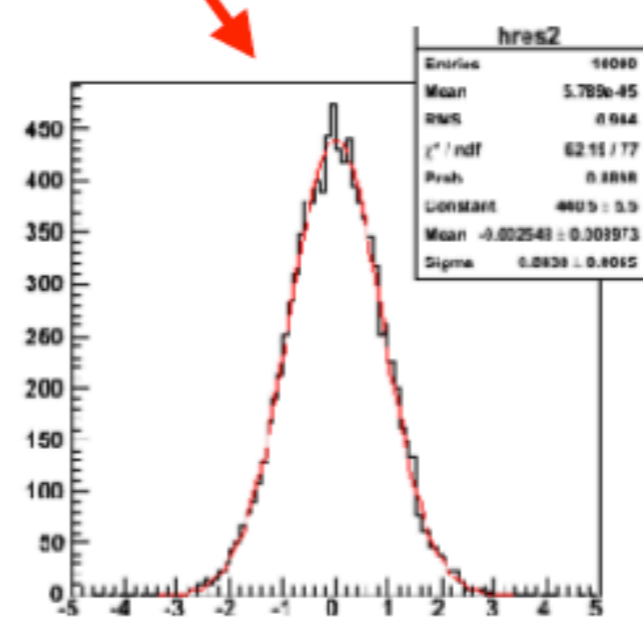
- Tracking by straight line : $y = a_y * z + b_y$



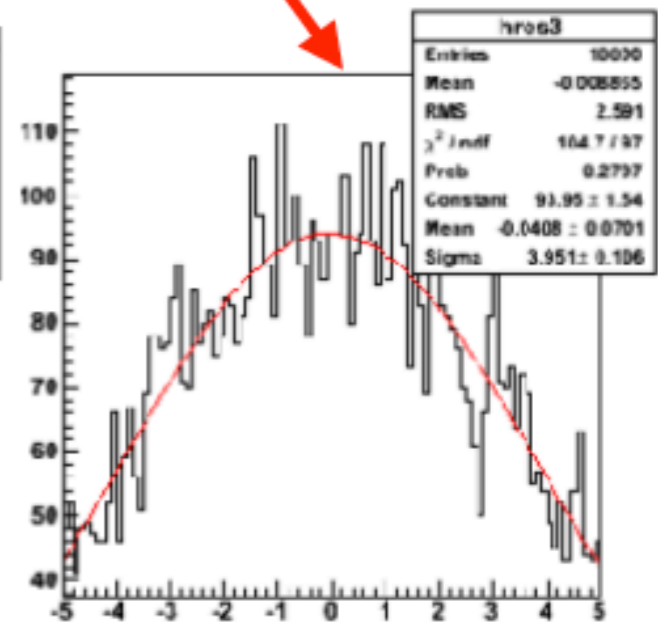
$\sigma = 1.03 \text{ um}$



$\sigma = 0.87 \text{ um}$



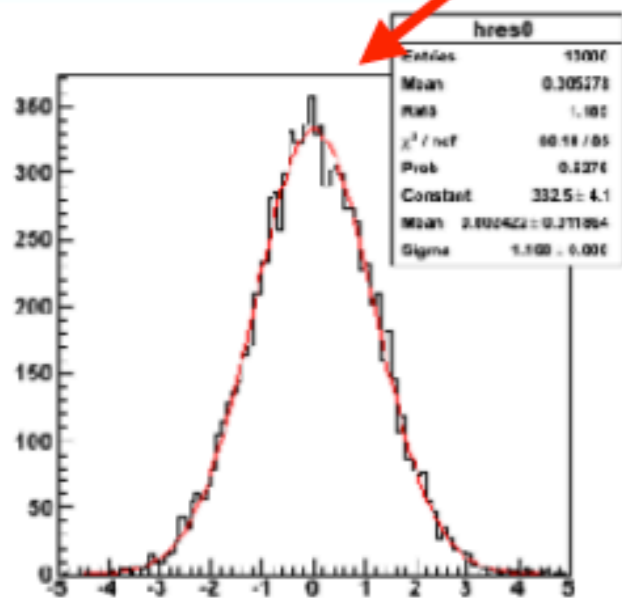
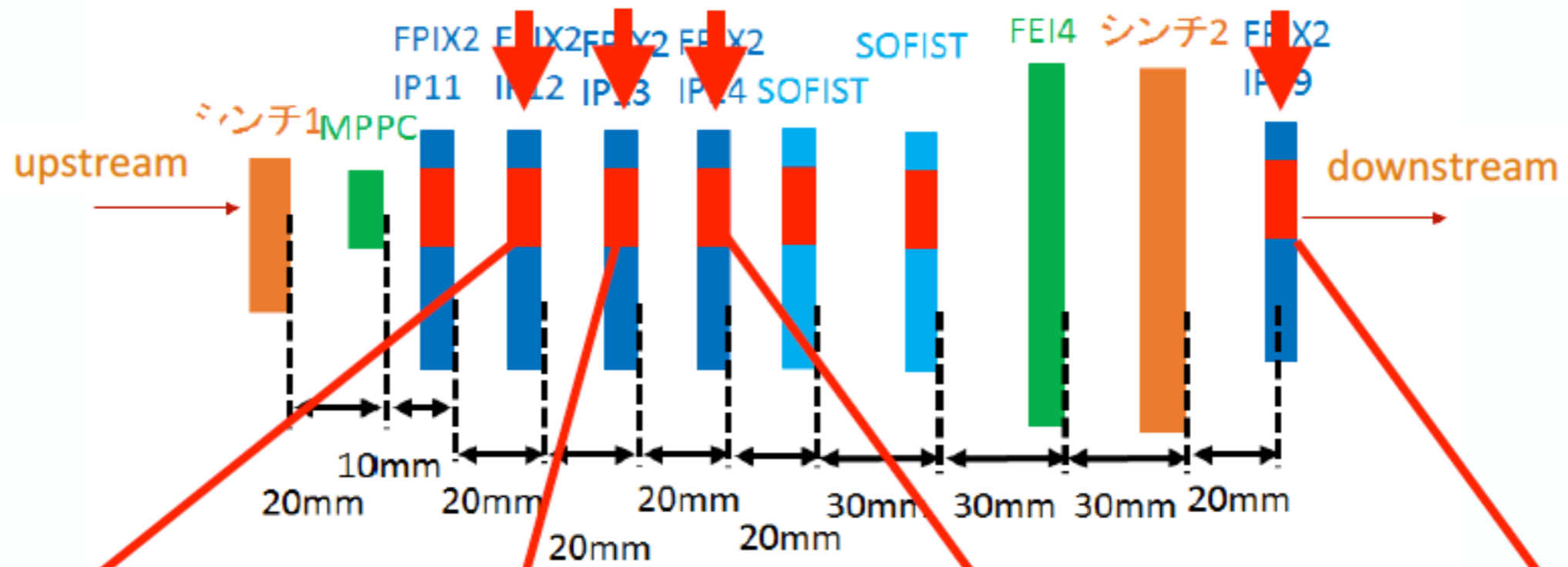
$\sigma = 0.88 \text{ um}$



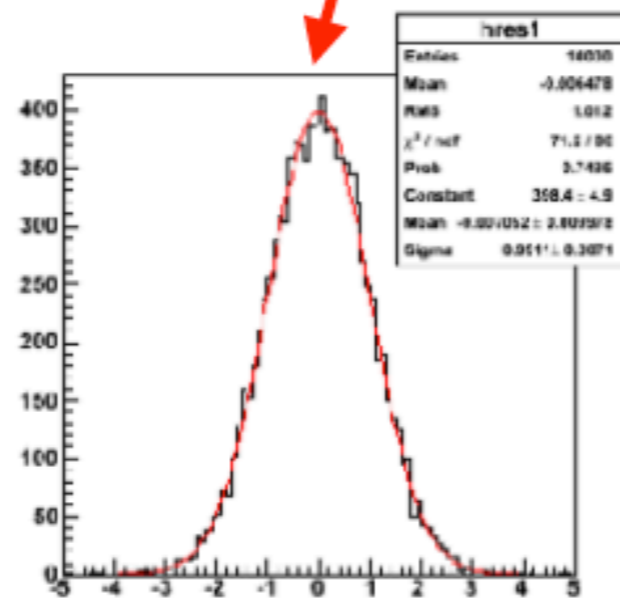
$\sigma = 3.95 \text{ um}$

Residual distribution by MC w/ intrinsic resolution=0.8 um

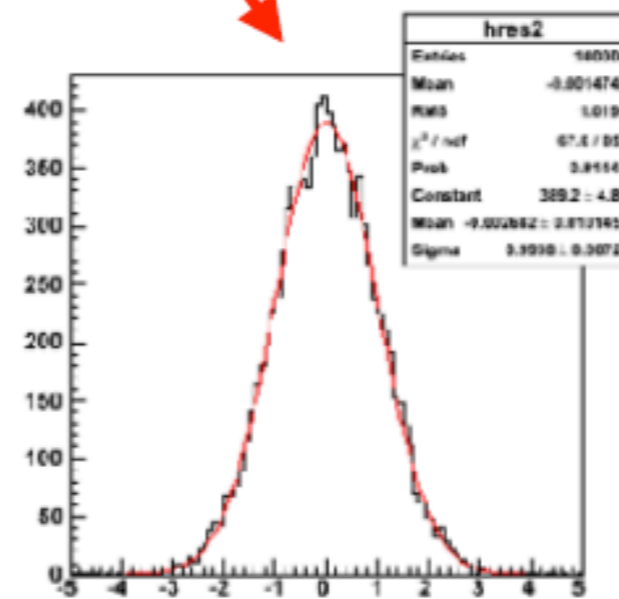
- Tracking by straight line : $y = a_y * z + b_y$



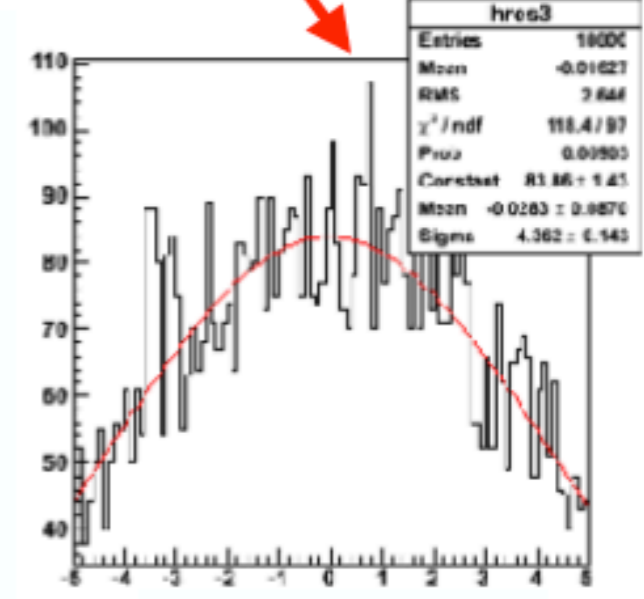
$\sigma = 1.17 \text{ um}$



$\sigma = 0.99 \text{ um}$



$\sigma = 1.00 \text{ um}$



$\sigma = 4.36 \text{ um}$